



# Tokyo Electron IR Day

January 20, 2021



# Forward Looking Statements

- Disclaimer regarding forward-looking statements

Forward-looking statements with respect to TEL's business plan, prospects and other such information are based on information available at the time of publication. Actual performance and results may differ significantly from the business plan described here due to changes in various external and internal factors, including the economic situation, semiconductor/FPD market conditions, intensification of sales competition, safety and product quality management, intellectual property-related risks, and impacts from COVID-19.

- Processing of numbers

For the amount listed, because fractions are rounded down, there may be the cases where the total for certain account titles does not correspond to the sum of the respective figures for account titles. Percentages are calculated using full amounts, before rounding.

- Exchange risk

In principle, export sales of Tokyo Electron's mainstay semiconductor and FPD production equipment are denominated in yen. While some settlements are denominated in dollars, exchange risk is hedged as forward exchange contracts are made individually at the time of booking. Accordingly, the effect of exchange rates on profits is negligible.

FPD: Flat panel display

# Agenda

1. Opening 15:30

2. Presentation 15:35

- Aiming to Enhance the Corporate Value over the Medium to Long Term
- Supercritical Drying Technology in the Cleaning Process for Leading-edge Devices
- New Platform for the Etch Systems to Enhance Productivity
- Latest Single Wafer Deposition Processes and Development Activities for the Future
- TEL's Strategies toward Digital Transformation

3. Q&A 16:35

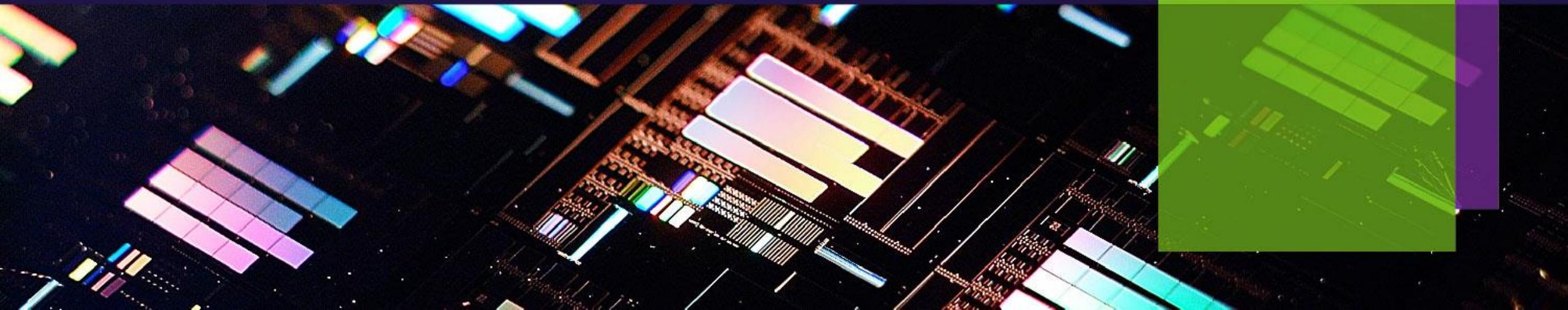
17:15

# Aiming to Enhance the Corporate Value over the Medium to Long Term

January 20, 2021

Toshiki Kawai

Representative Director, President & CEO



## First and Foremost

**We want to express our deepest sympathies to all those who have been affected by COVID-19 or other natural disasters over the past year**

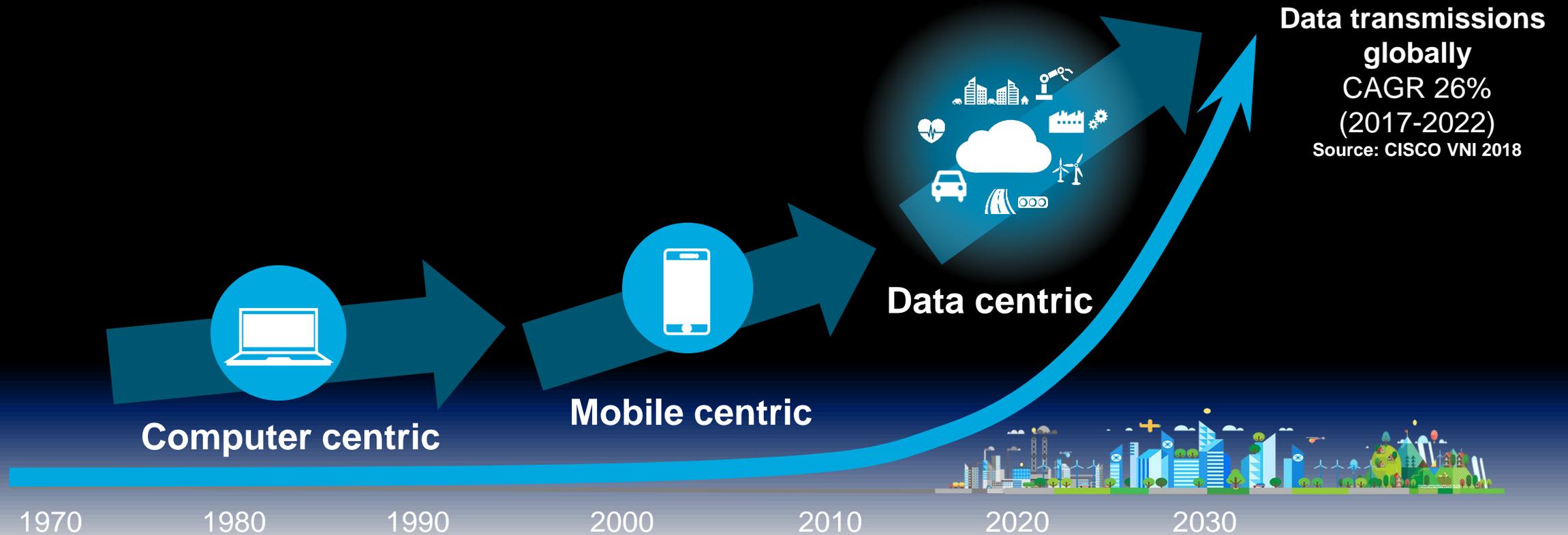
## A Year of Steady Progress

**TEL's business made steady progress**  
**Reaffirmed TEL's driving forces globally**  
**Honored the TEL Values and shared them**  
**with employees**



Pride • Challenge • Ownership •  
Teamwork • Awareness

# Beginning of Big Data Era



**A phase of higher growth with this data-centric era  
“Big years” ahead toward a future shift from selling products  
to selling value**

# Changes in Society Occurring Amid COVID Crisis

Remote work  
Online classes  
Telemedicine  
Video streaming services  
Online games  
Drug development using AI

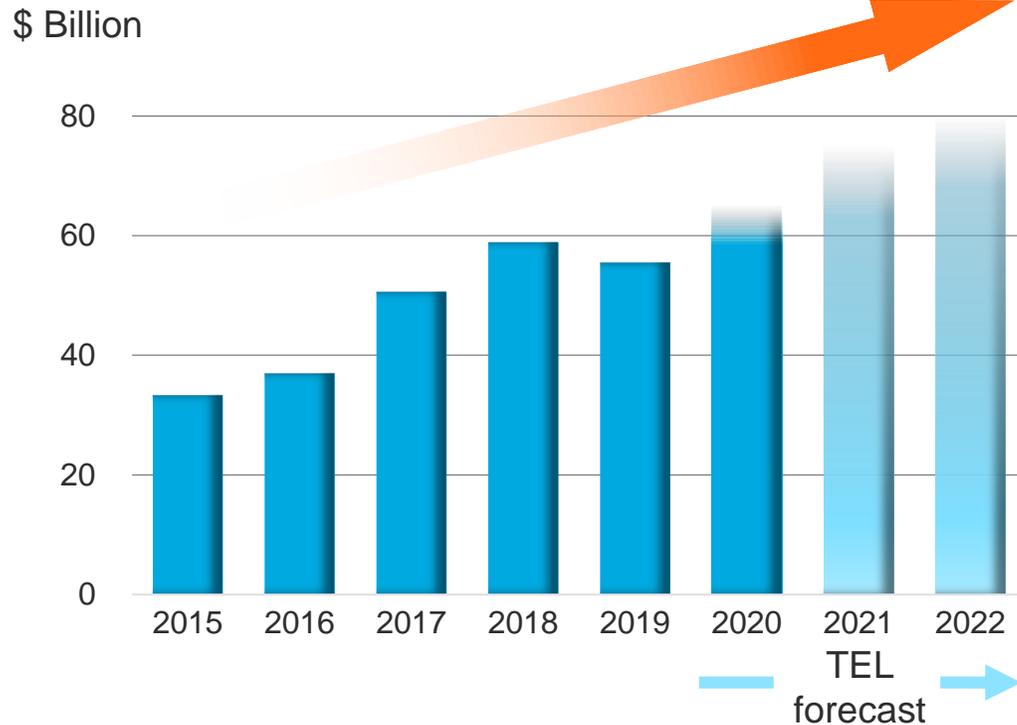
**IoT AR/VR/MR AI**  
**5G/6G CLOUD**



**Transition to a data  
society will  
accelerate**

**ICT\* being implemented widely around the world to  
build a strong and agile society**

# WFE\* Market



**2021:**  
Increased demand for advanced semiconductors for hyperscale data centers and 5G smartphones will drive WFE market

**Memory:** Recovery in investment on liquidation of inventories

**Logic/Foundry:** Continued stable and high level of investment

**Last year's record WFE will continue into 2021 and beyond, leading to Big Years**

# Initiatives to Create New Value Toward Coming Big Years

## Tokyo Electron Technology Solutions (TTS) New production buildings began operation

Tohoku (Iwate): Jul. 2020-



Yamanashi: Aug. 2020-



**Enhance production structure to swiftly prepare for future  
rise in demand**

# Initiatives to Create New Value Toward Coming Big Years

TEL Digital Design Square  
(Sapporo):  
Began operation Nov. 2020



Miyagi Technology Innovation Center:  
Completion scheduled for Sep. 2021



**Meet needs for increasingly diverse extreme scaling  
technology**

# Initiatives to Create New Value Toward Coming Big Years

¥400B in R&D investment in the three years from FY'20



**Continue proactive R&D investment to achieve Medium-term Management Plan and maximize capture of growth potential for the future**

# Initiatives for the Environment

Contribution from  
business activities

**Reduce  
semiconductor power  
consumption**



Our product initiatives

**Energy saving, high  
operation rate and high  
yield equipment**



**With our technology both support the development of  
ICT and reduce environmental burden**

# Environmental Medium-term Targets for 2030

## CO<sub>2</sub> emissions reduction targets

### Products



**30%** reduction  
per wafer (vs 2018)

Note: Of the total CO<sub>2</sub> emissions from TEL's value chain, approx. 87% are generated during product use

### Facilities



**70%** reduction  
of total emissions (vs. 2018)

Reduce energy consumption at each facility by 1% per year (per-unit basis, annual target, YoY)

**Toward 100% renewable energy use**

### Long-term goal (2050)

As a leading corporation in environmental management, Tokyo Electron works actively to conserve the global environment. We strive to contribute to the development of a dream-inspiring society by proactively promoting the reduction of the environmental burden of both our products and facilities, and at the same time, providing evolutionary manufacturing technologies that effectively reduce the power consumption of electronic products.

**Support the development of a sustainable society through proactive initiatives for environmental issues**

# As a SPE and FPD equipment maker

Corporate  
Philosophy

We strive to contribute to the development of a dream-inspiring society through our leading-edge technologies and reliable service and support.

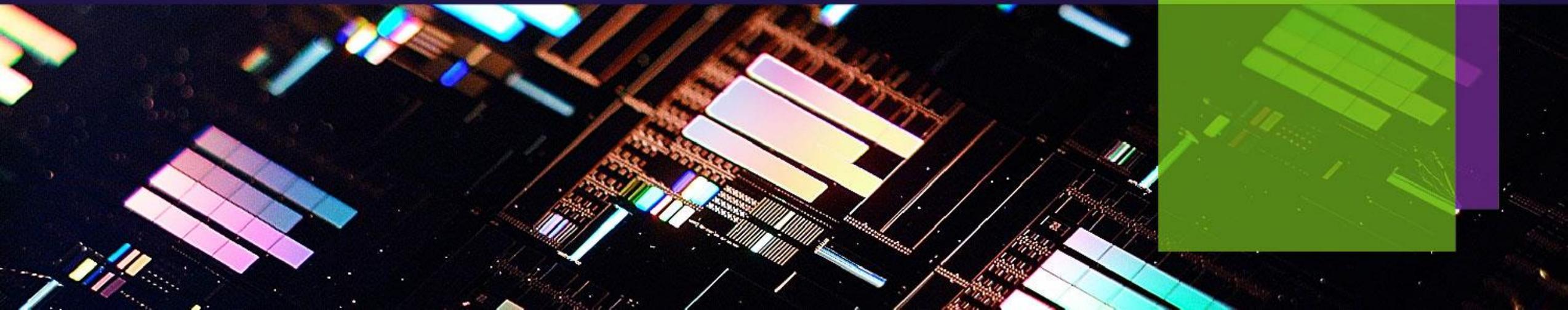


# Supercritical Drying Technology in the Cleaning Process for Leading-edge Devices

January 20, 2021

Keiichi Akiyama

VP & General Manager, CTSPS BU



# Release of New Product with Supercritical Drying Technology

## TEL Announces the Launch of CELLESTA™ SCD, a Single Wafer Cleaning System

Tokyo Electron (TEL) announced today the launch of the CELLESTA™ SCD single wafer cleaning system, scheduled for release in January 2021.

TEL's CELLESTA series of products are widely used for cleaning silicon wafers in the semiconductor manufacturing process. The soon-to-be-released CELLESTA SCD integrates a dedicated supercritical drying chamber on the mass production-proven CELLESTA platform.

In wafer cleaning, it has been customary to employ low surface tension alcohol solutions in the drying process. However, due to continued semiconductor scaling and adoption of multi-layer structures in highly advanced devices, pattern collapse in the drying process has become one major issue. In response, TEL has developed a pattern collapse-free drying method that uses a supercritical fluid, bringing the technology to the market as equipment for mass production.

With the addition of CELLESTA SCD and its dramatically improved cleaning and drying technologies to the existing line of single wafer cleaning systems, TEL is meeting advanced technological needs in semiconductor manufacturing to drive further growth of the semiconductor industry.

“CELLESTA SCD offers an innovative technological solution to the wafer-drying challenges in the post cleaning process for manufacturing advanced semiconductor devices,” said Keiichi Akiyama, Vice President & General Manager, CTSPS BU at TEL. “We will continue to leverage our ability to develop innovative technologies and deliver high value-added products, providing optimum solutions for technological issues associated with the most advanced semiconductor devices.”

TEL will be showcasing CELLESTA SCD at SEMICON Japan 2020 Virtual.  
Please visit our virtual booth during the show.  
Period: 2020/12/11 ~2021/1/15

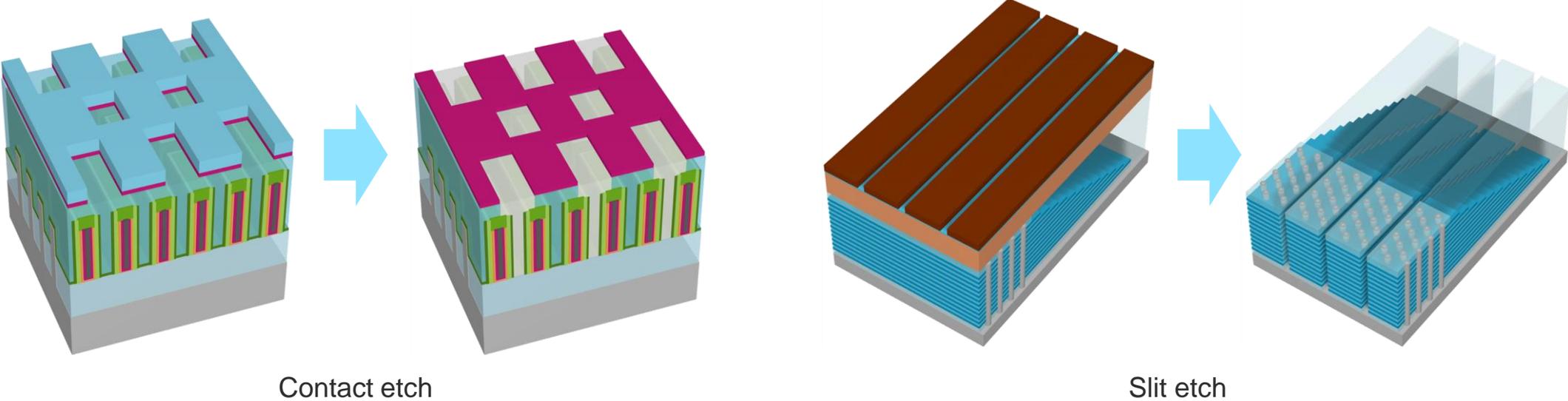
CELLESTA is a registered trademark or trademark of Tokyo Electron Group in Japan and/or other countries.



CELLESTA™ SCD  
SCD: Supercritical dry

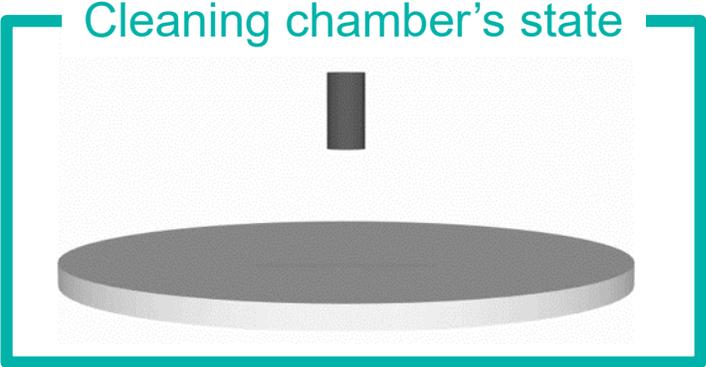
# Cleaning Process in Semiconductor Manufacturing

## Post-etch cleaning

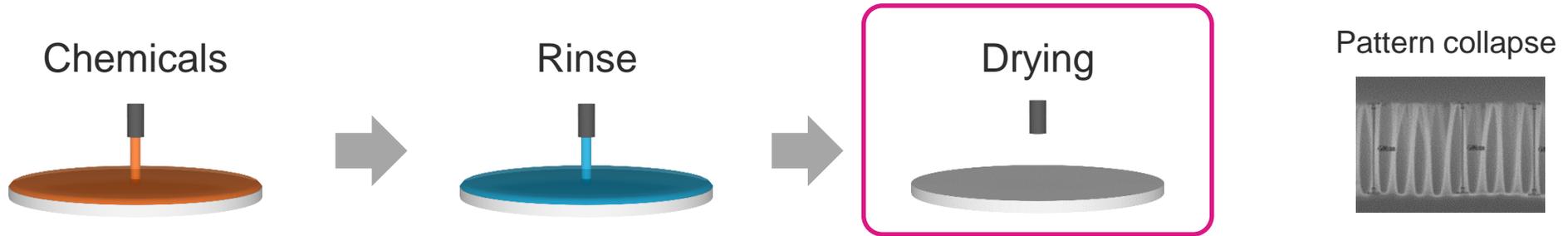


## General cleaning process

- Cleaning by **chemicals**
- **Rinse**
- **Drying**

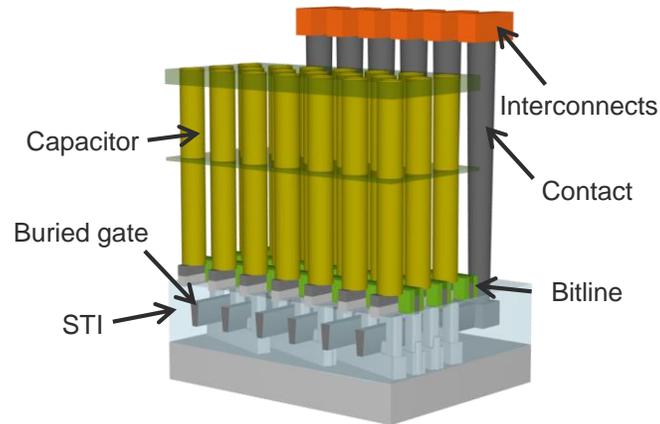


# Technology Challenges in Cleaning for State-of-the-Art Devices

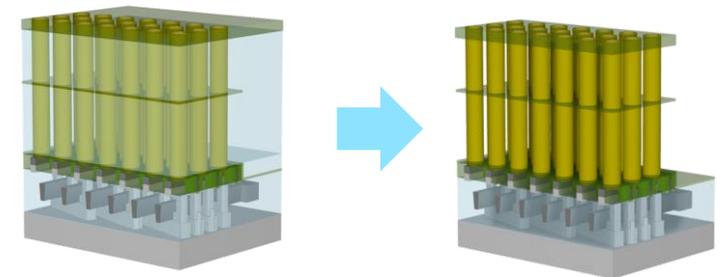


## ■ DRAM

- Post-STI etch cleaning
- Mold wet etch after capacitor electrode formation

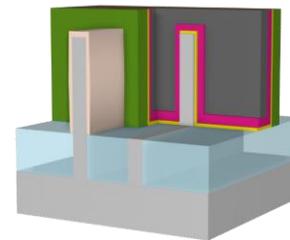


## Wet etch

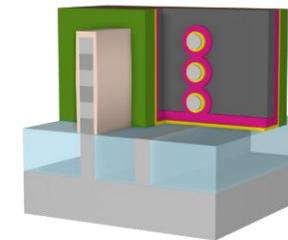


## ■ Logic

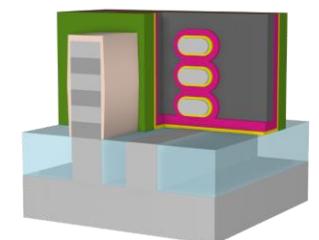
- Post-fin etch cleaning
- Post-nanowire/nanosheet formation cleaning



FinFET



Nanowire



Nanosheet

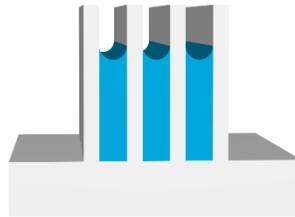
Drying technology more difficult due to further scaling and higher aspect ratios in device manufacturing

# Pattern Collapse Mechanism and Solution

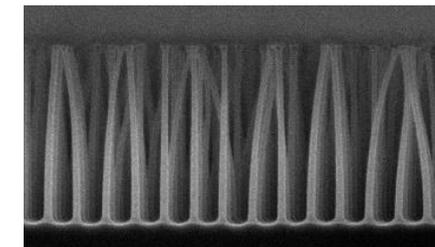
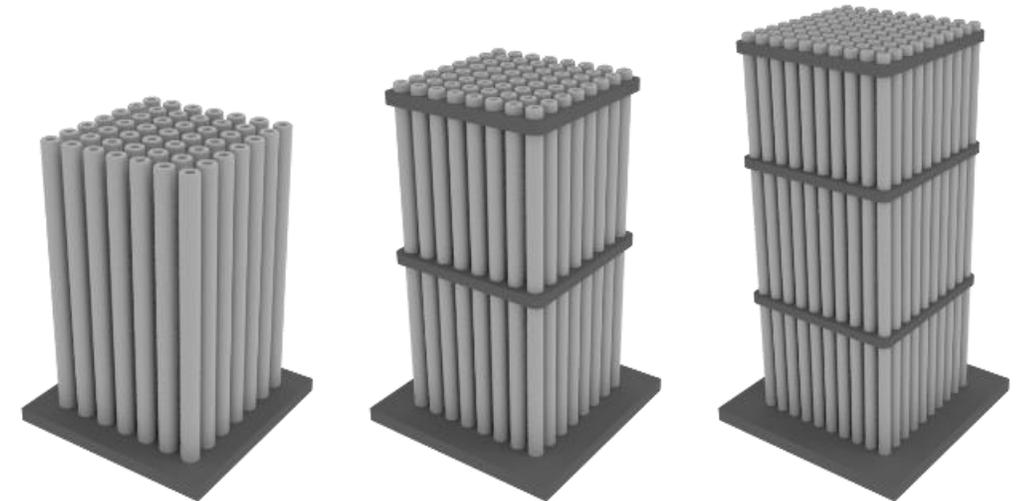
Surface tension\*



Before drying



After drying



\*Surface tension: The tendency of a liquid or solid to reduce its surface area

As aspect ratios have become higher, the collapse prevention approach of chemical replacement for lowering surface tension, surface modification, etc., is reaching its limit

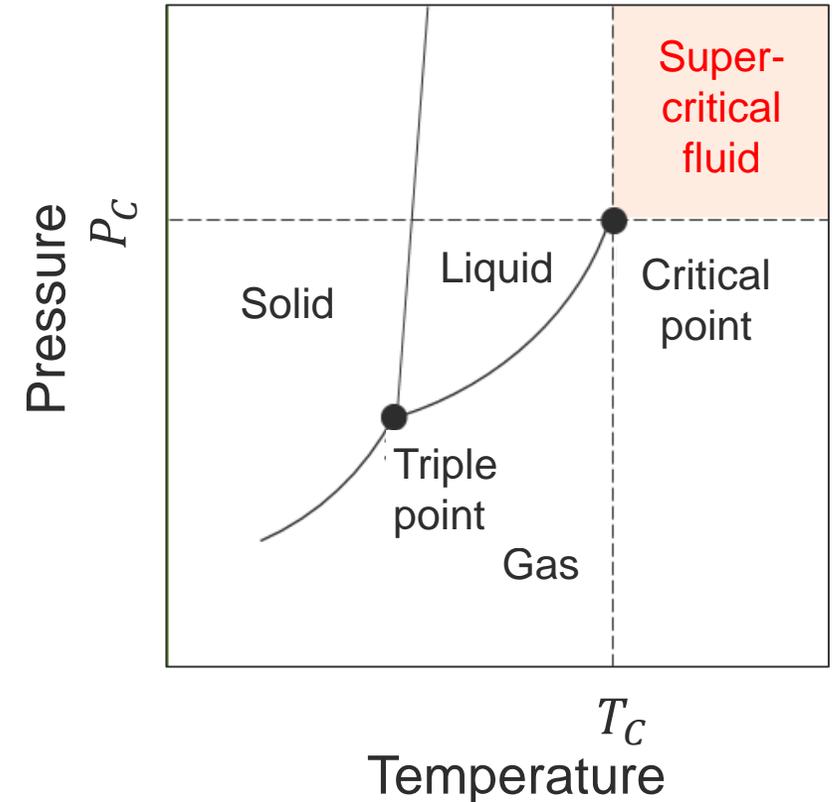
# Next Generation Drying Technology

- The next generation drying technologies are supercritical dry and sublimation dry
- As supercritical dry is the most effective solution for the issues in drying technology, TEL has released the CELLESTA™ SCD for mass production
- Supercritical dry is expected to be used in a wide range of applications, including for complex structures like capacitor electrodes and fragile films like PCRAM memory cells

	Application	Residue	Oxidation/material loss
Supercritical dry	Usable for complex and/or high aspect ratio structures	Very little	No
Sublimation dry	Not suitable for stacked or fragile structures	Significant	Yes

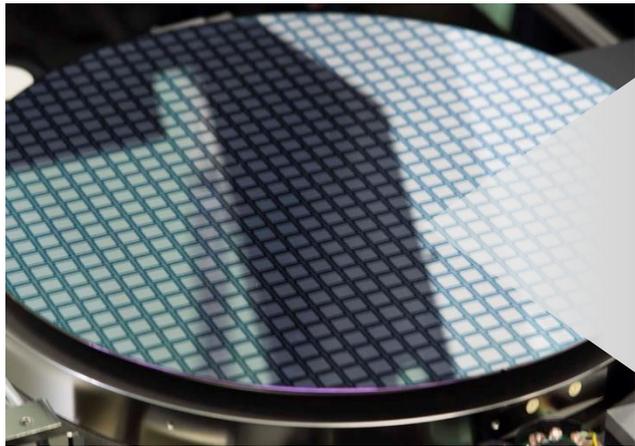
# Supercritical Drying Technology

- What is supercritical?
  - The state where temperature and pressure are above their critical point
  - Holds properties between those of liquid and gas
  - Surface tension is zero
- Challenges for introducing in semiconductor production process
  - Stable operation at pressure regions hitherto unused
  - Particle control at the nano-level



Effective against pattern collapse because surface tension is theoretically zero  
Particle control is required at the nano-level for leading-edge processes

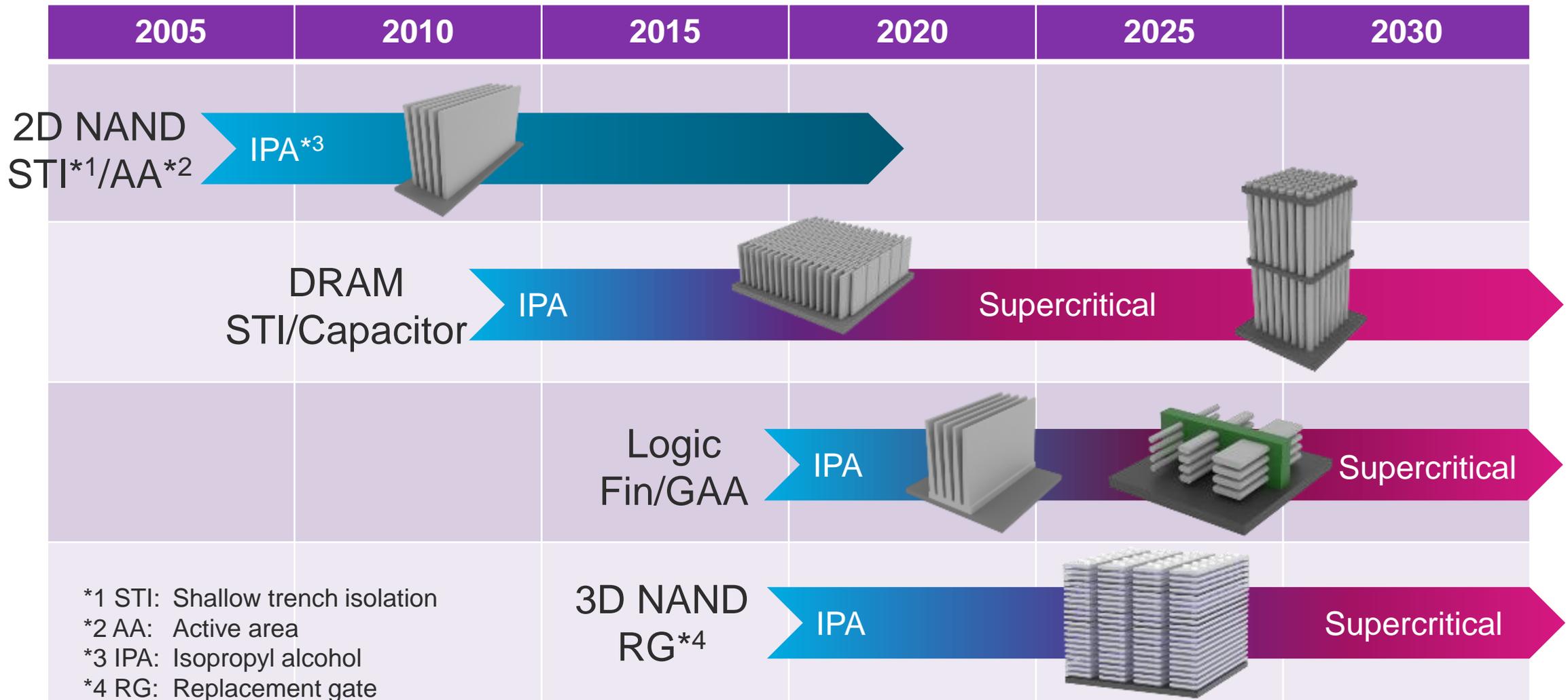
# Supercritical Drying Technology



	Traditional drying	TEL's supercritical drying
Top View		
Side View		

Supercritical drying technology prevents pattern collapse

# Drying Technology Roadmap



# Summary

- TEL is proposing supercritical drying technology for pattern collapse, a technological issue in wafer cleaning
- We will continue to offer new technologies and solutions to various technological issues in wafer cleaning for leading-edge devices as a partner of semiconductor manufacturers



CELLESTA™ Pro SPM



CELLESTA™ -i



EXPEDIUS™ -i



NS300Z

# New Platform for the Etch Systems to Enhance Productivity

January 20, 2021

Isamu Wakui

VP & General Manager, ES BU



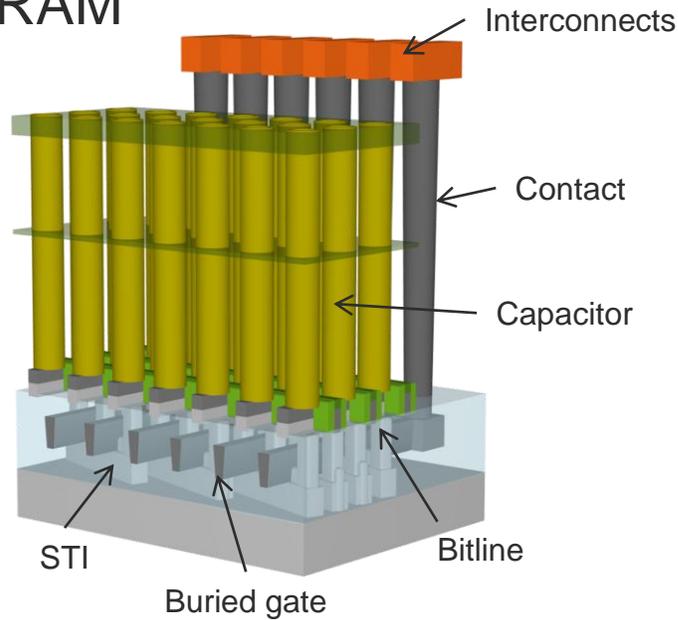
# Business Opportunities and Basic Strategy

- Continued high level of investment expected in the etch systems market driven by 3D NAND and patterning
- Focus on HARC, patterning and interconnects, which leverage TEL's strengths  
Aiming to raise share and profitability
- Continuing proactive investment toward further market growth in future

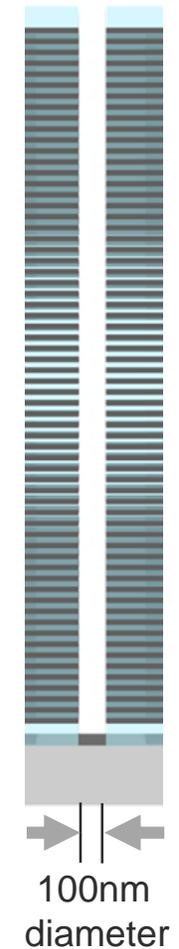
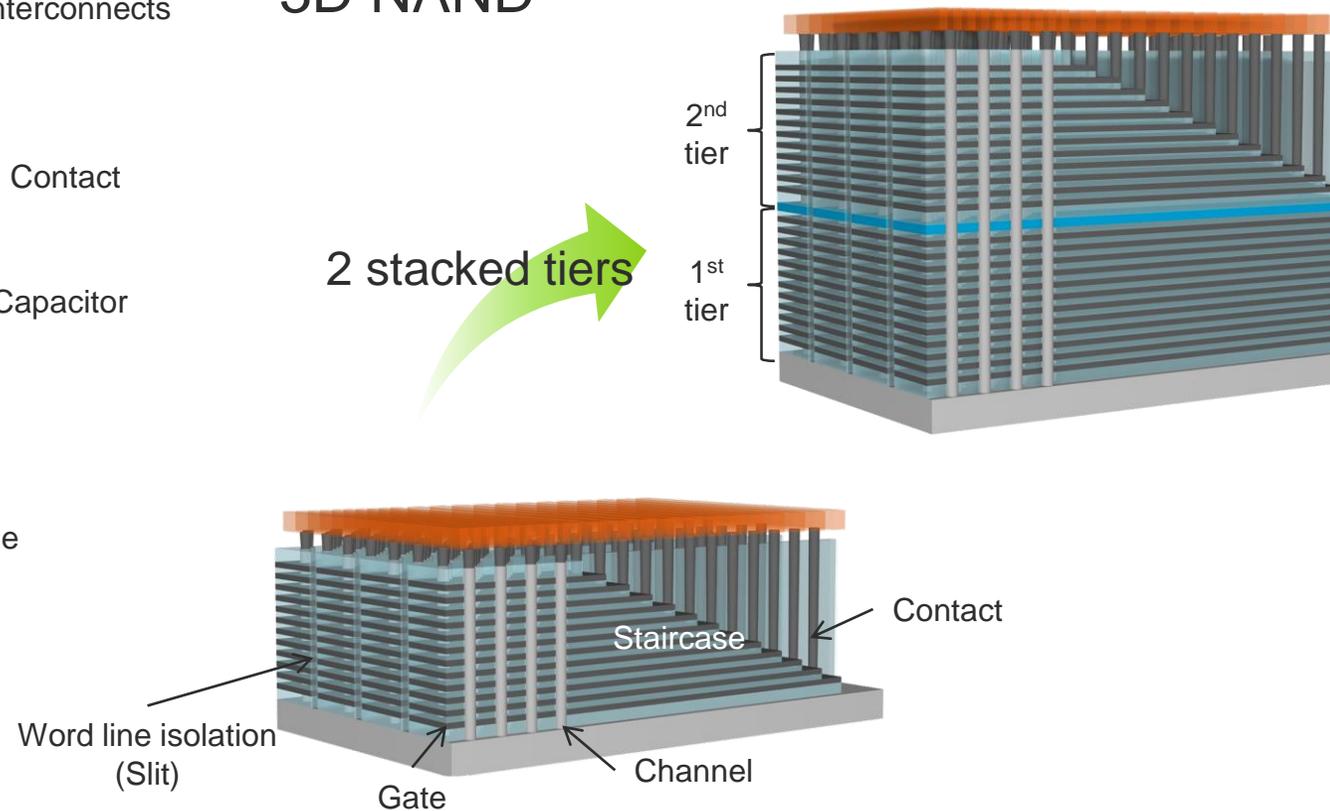
# Challenges in Etch for Memory

Aspect ratio = 50-70:1

## DRAM

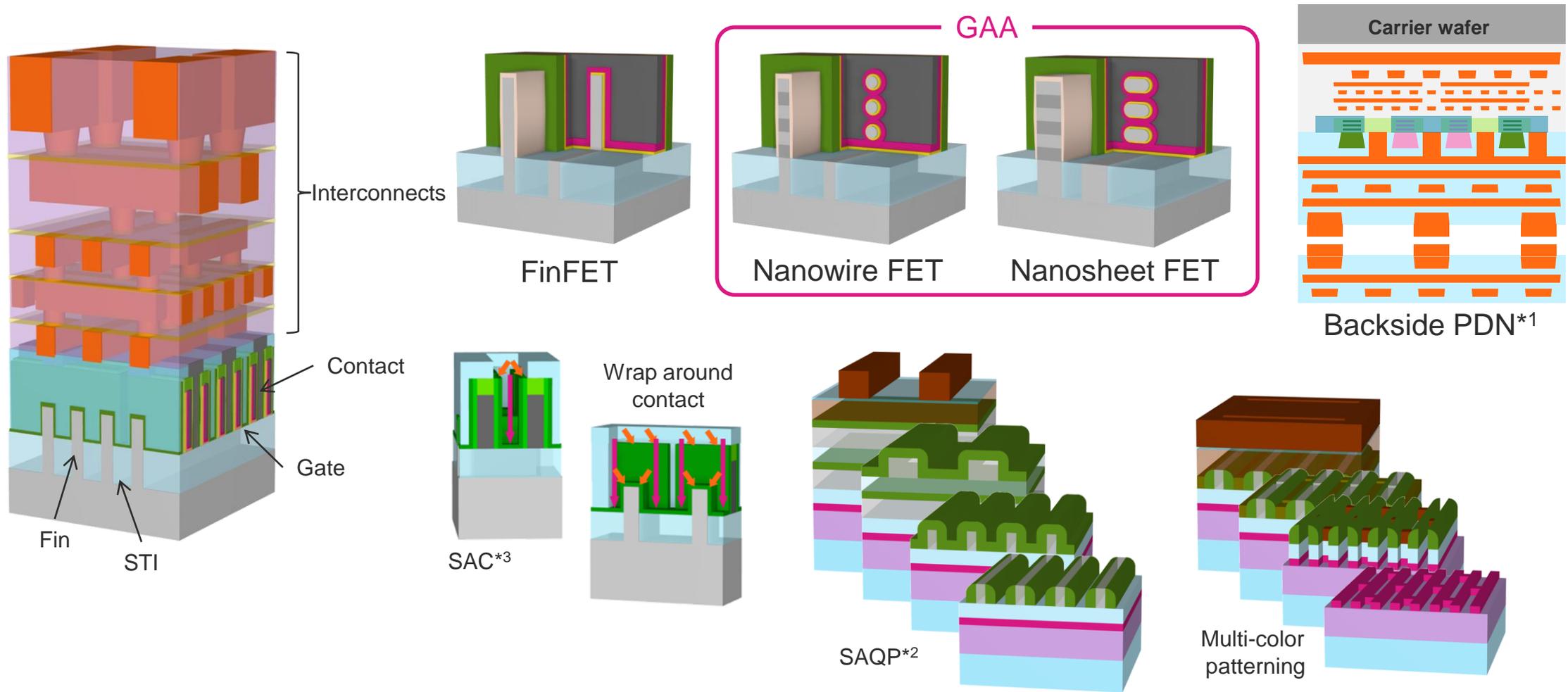


## 3D NAND



As the number of layers and aspect ratio increase, it is necessary to balance processing performance and productivity

# Challenges of Etch for Logic



Flexible equipment layout sought for diversified etch processes

\*1 PDN: Power delivery network

\*2 SAQP: Self-aligned quadruple patterning

\*3 SAC: Self-aligned contact

# History of TEL Etch Systems

 4, 5, 6 inch

 200 mm

 300 mm

1980's

1990's

2000's

2010's



## TEL Etch 480

TEL's first single wafer dry etch tool



## UNITY™

TEL's first original vacuum multi-chamber tool



## Telius™

World's first parallel-chamber tool



## Tactras™

World's first addition of X axis movement to robot arm  
Realized 6 chambers in one system



## TE5000

TEL's first original dry etch tool



## TE8500



## UNITY™ II

TEL's first platform with multi-chambers



## Tactras™ BX

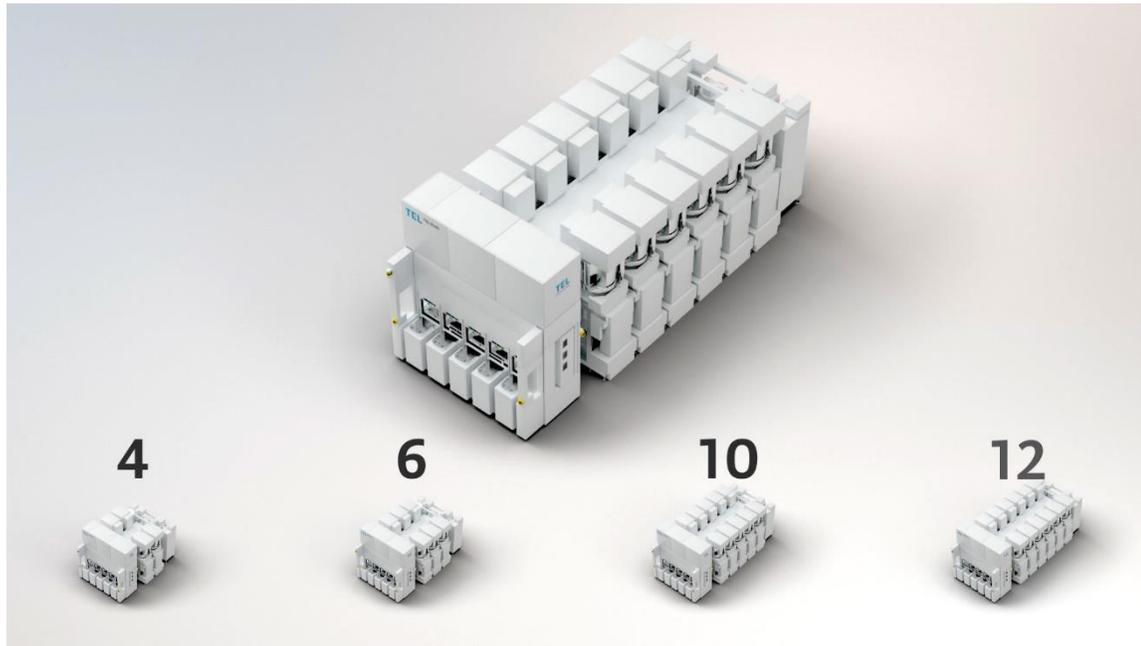
Realized 8 chambers in one system

# Episode™ UL Features

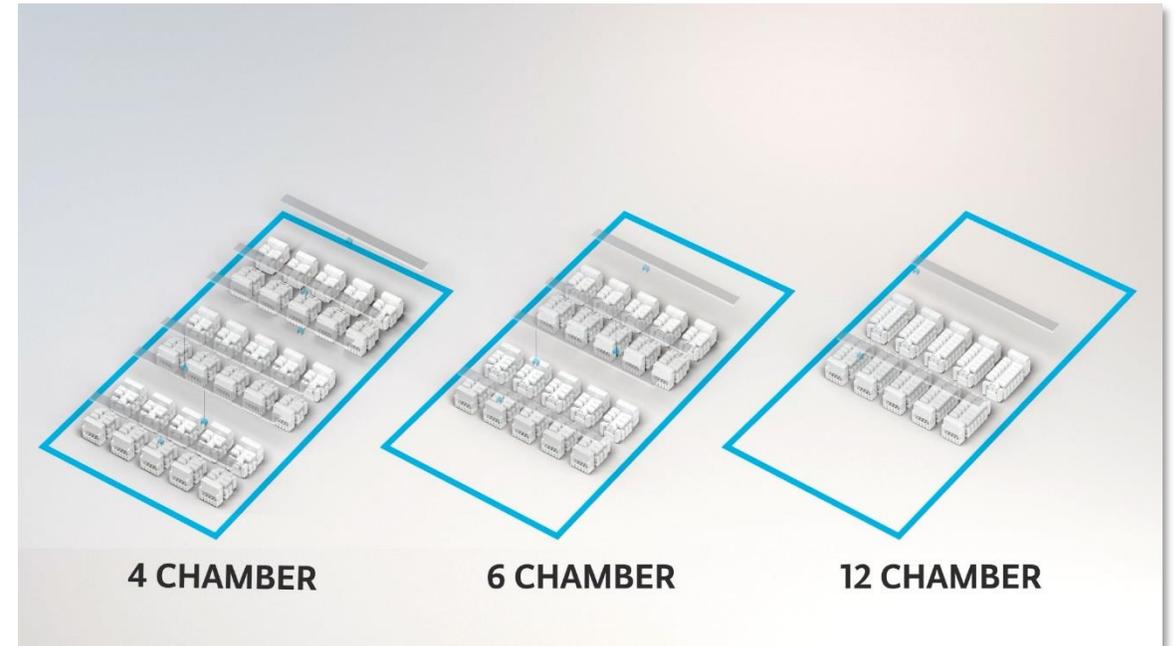


Flexible layout available to accommodate needs  
Improved productivity through space saving and smart tools

# Episode™ UL: Layout

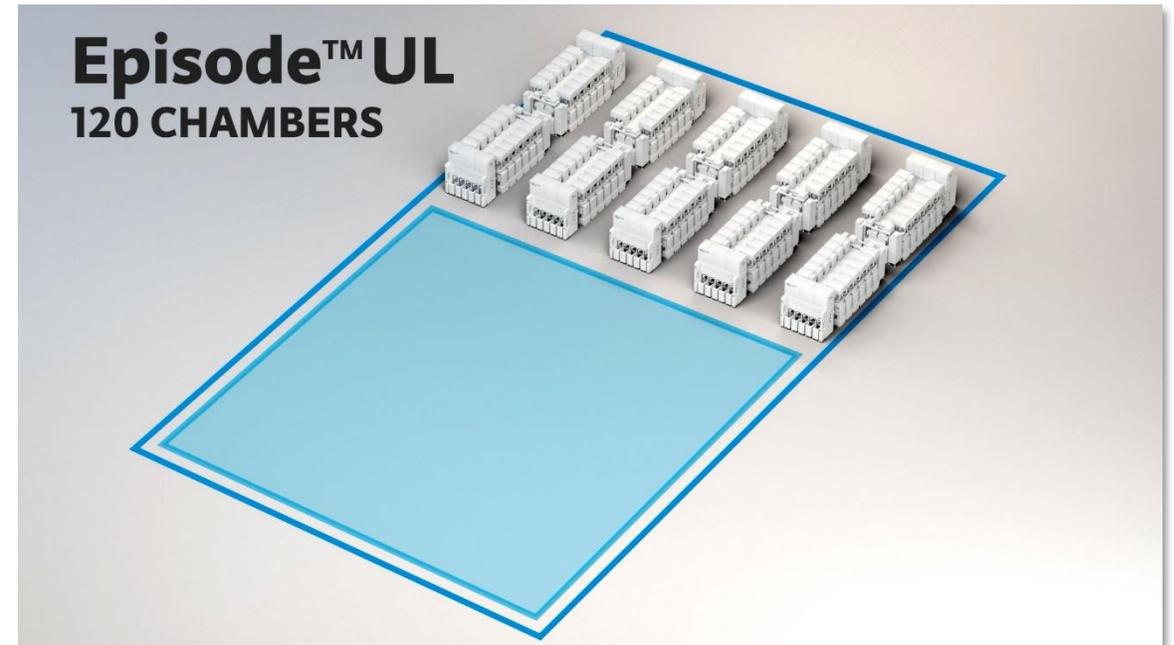
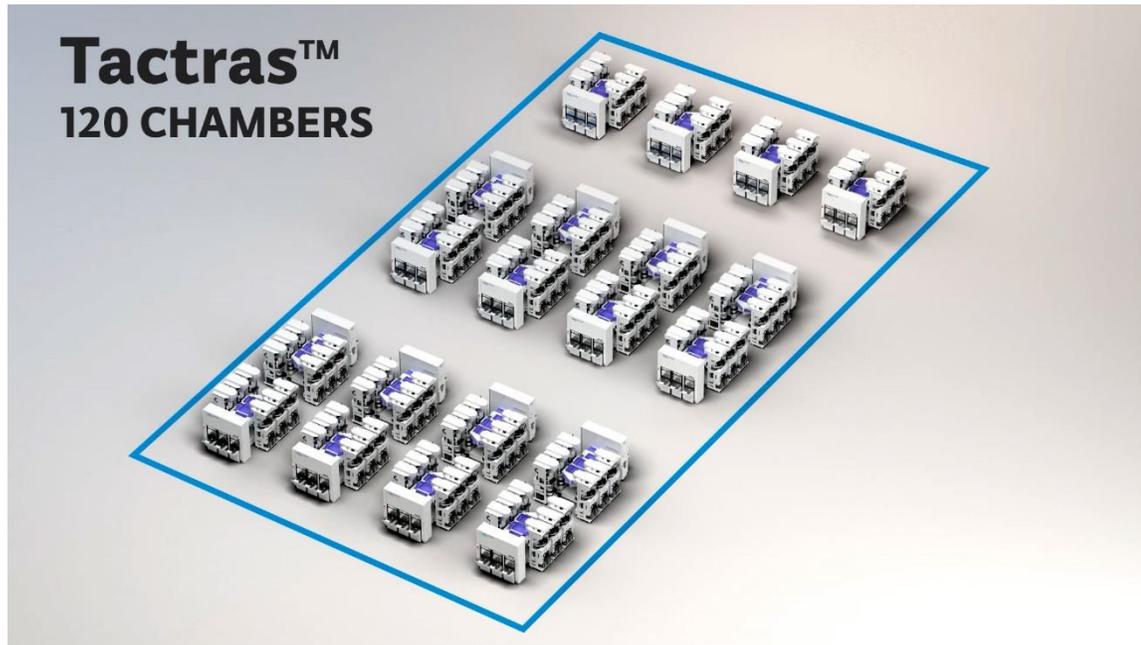


Select from 4 options  
4, 6, 10, and 12 chamber designs



Flexible layout available to accommodate  
fab space and target processes

# Episode™ UL: Space



Significantly reduced footprint per chamber

# Episode™ UL: Smart Tools

**AUTOMATED  
PARTS EXCHANGE**



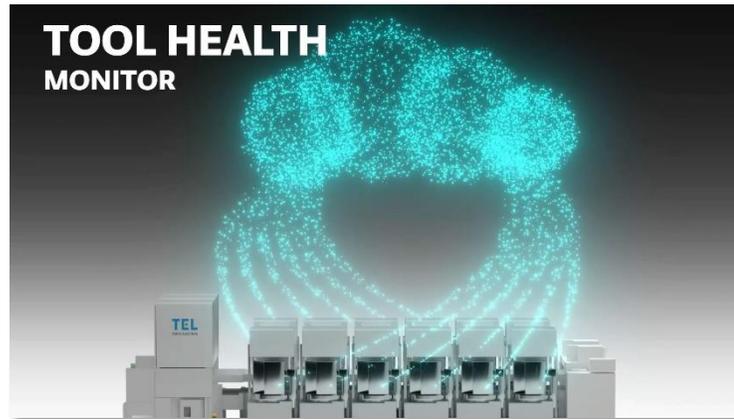
**10X FASTER  
SENSING**



**BIG DATA  
ANALYSIS**



**TOOL HEALTH  
MONITOR**



**USER FRIENDLY  
INTERFACE**



Includes automated parts exchange functions, multiple sensors and a high-speed control system  
Autonomous process control possible through big data analysis using TEL's own smart tools

# Episode™ UL Movie

# Summary

- Flexible layout:
  - Capable of selecting any number of chambers, from 4 to 12
- Space:
  - Significantly reduced footprint per chamber
- Smart Tools:
  - Includes automated parts exchange functions, multiple sensors and a high-speed control system

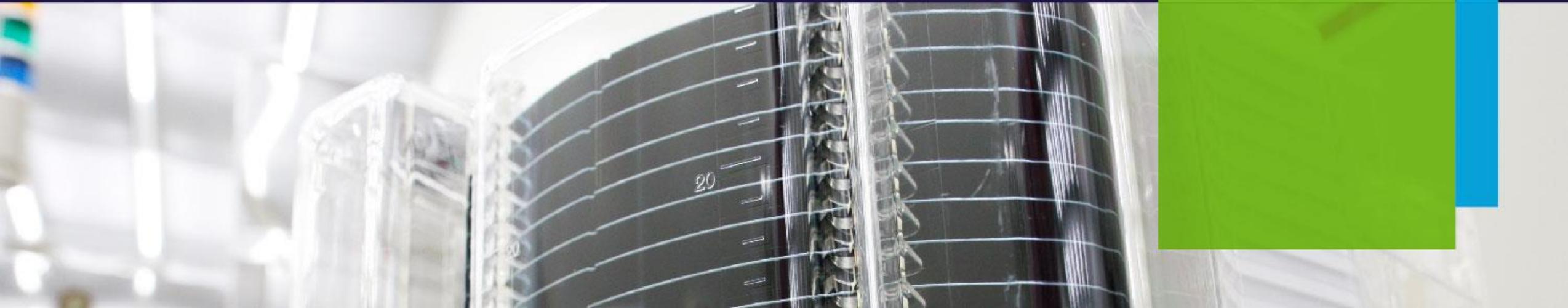
Autonomous process control possible through big data analysis using TEL's own smart tools

# Latest Single Wafer Deposition Processes and Development Activities for the Future

January 20, 2021

Hiroshi Ishida

VP & General Manager, TFF BU



# Thin Film Formation Product Lineup

**Furnace**  
TELINDY PLUS™



**Semi-batch ALD**  
NT333™



**Single Wafer Deposition**  
Triase+™



**MRAM MTJ Formation**  
EXIM™



## Oxidation / CVD / ALD / PVD

### Batch Process\*

Process: Oxidation/CVD/ALD  
Reaction: Thermal/Plasma  
Material: SiO<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/High-k/Metal  
Feature: 100 to 150 wafers/batch

### Semi-batch Process

Process: ALD  
Reaction: Thermal/Plasma  
Material: SiO<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/High-k  
Feature: 5 to 6 wafers/batch

### Single Wafer Process

Process: CVD  
Reaction: Thermal/Plasma  
Material: Metal/High-k/Ferroelectric  
Feature: Superior step coverage

Process: PVD  
Reaction: Thermal/Plasma  
Material: Magnetic material/Metal  
Feature: Multi-film stacking

\* Installed base >10,000 @ 300mm

# Triase<sup>+</sup>™ EX-II™ Advance: TiN for Super High Aspect Ratio

## ■ Features

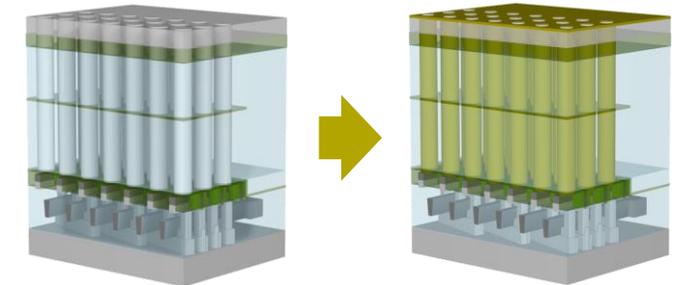
- State-of-the-art advanced sequential flow deposition (TiN)
- High precursor and gas supply provides superior step coverage ratio for the most advanced memory devices
- Thin film continuity (Continuous film at  $<10 \text{ \AA}$ )
- Excellent thickness uniformity ( $1\sigma < 1\%$ )
- Wide temperature capability (400 to 600°C)
- High speed pressure control enables higher productivity

## ■ Applications

- DRAM capacitor electrode
- 3D NAND word line barrier
- Other high surface area structures

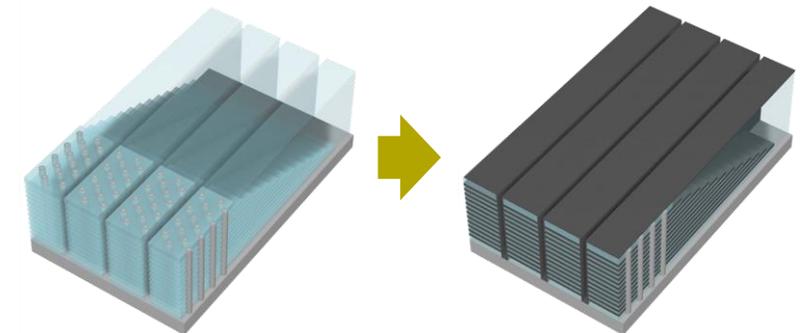
DRAM

Bottom electrode



3D NAND

Word liner barrier



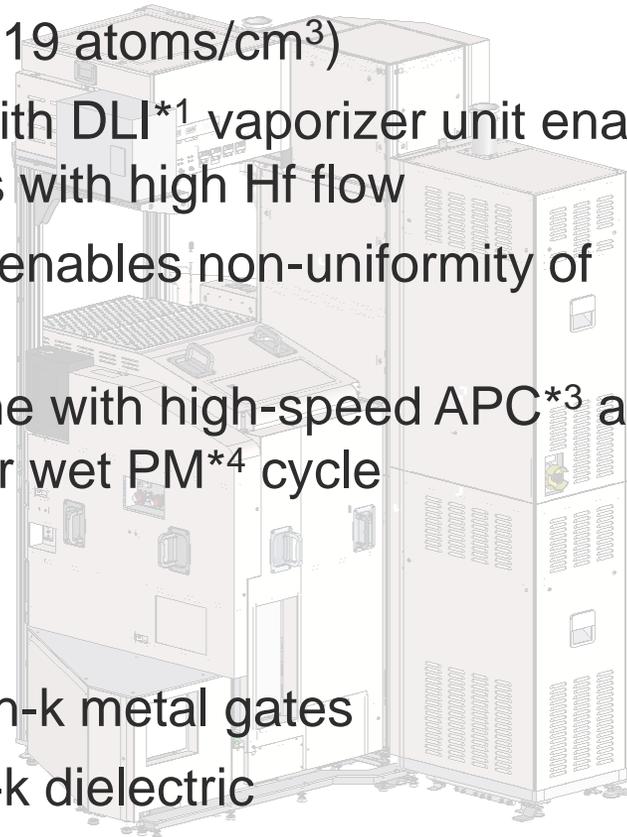
# Triase<sup>+</sup>™ EX-II™ HK: High Quality High-k Dielectric

## ■ Features

- Designed for HfO process @ ~400°C and ultra low carbon (~1E19 atoms/cm<sup>3</sup>)
- Liquid Hf precursor with DLI\*<sup>1</sup> vaporizer unit enables ideal ASFD\*<sup>2</sup> process with high Hf flow
- Unique gas insertion enables non-uniformity of < 1% within wafer
- Enhanced exhaust line with high-speed APC\*<sup>3</sup> and 100A piping for longer wet PM\*<sup>4</sup> cycle

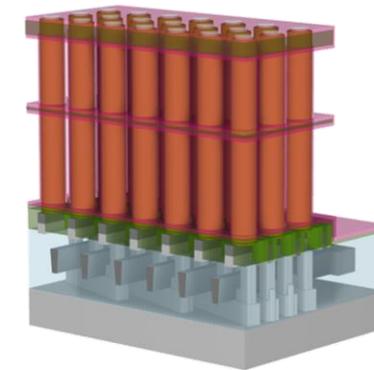
## ■ Applications

- DRAM peripheral high-k metal gates
- 3D NAND block high-k dielectric



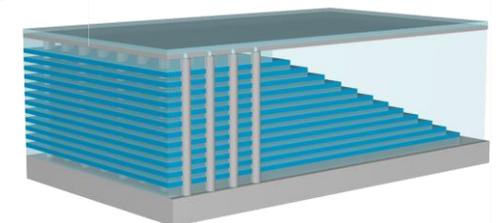
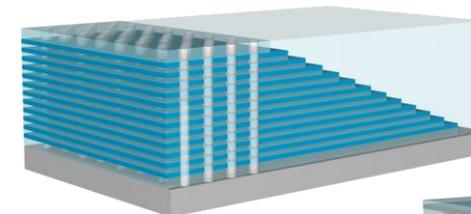
DRAM

High-k dielectric



3D NAND

Block high-k ~ core oxide dep



\*1 DLI: Direct liquid injection

\*2 ASFD: Advanced sequential flow deposition

\*3 APC: Auto pressure control valve

\*4 PM: Preventative maintenance

# Triase<sup>+</sup>™ EX-II™ HK: High Quality High-k Dielectric

## Uniformity

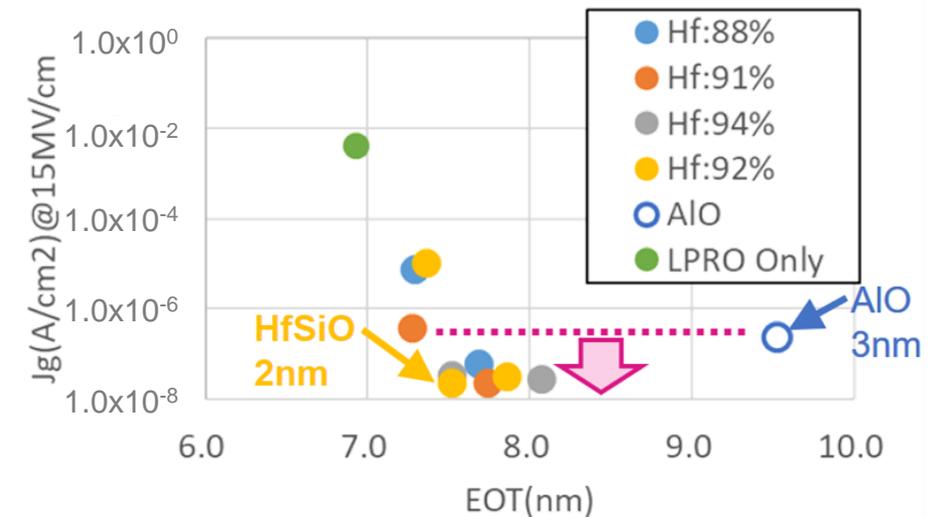
	HfSiO	HfO
Hf conc. (%)	73	100
Map		
Ave. thick (Å)	46.9	33.0
Range (%)	0.78	0.85
1σ (%)	0.16	0.19
Ave. - IL	32.0	19.9

## Coverage

TOP	A		113
	B		100
T-C	C		102
	D		103
CTR	E		100
	F		98
C-B			100
			100
BTM			98
			98
Coverage Min / B			<b>98%</b>

Hole aspect ratio = 55:1

## Leak current



Leak current of HfSiO 2nm-thick is smaller than that of AIO 3nm-thick on TEL MOS capacitor

Enables high-k thin film formation on high aspect ratio structures

# Triase<sup>+</sup>™ EX-II™ MS: Multi-source Supply for Controllable Film Composition

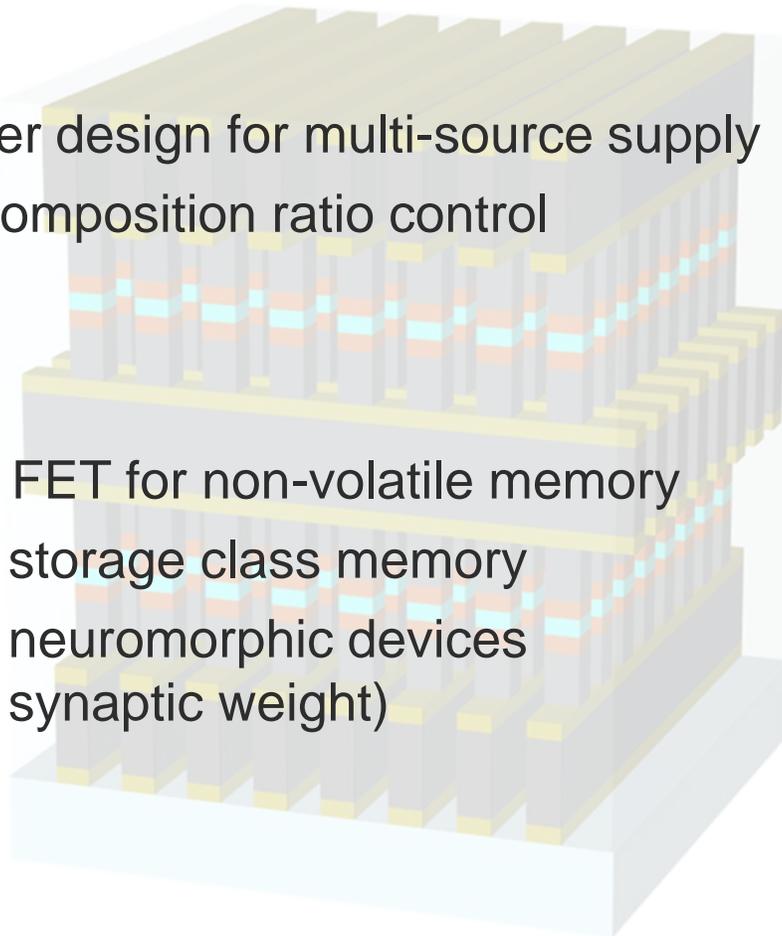
Under development

## ■ Features

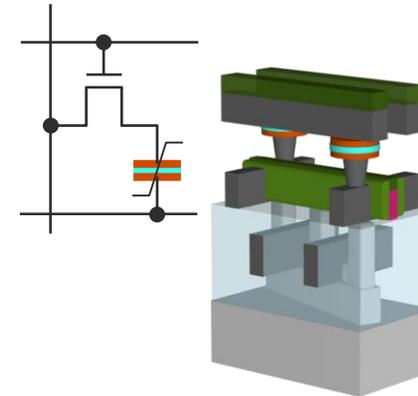
- New Chamber design for multi-source supply
- Capable of composition ratio control

## ■ Applications

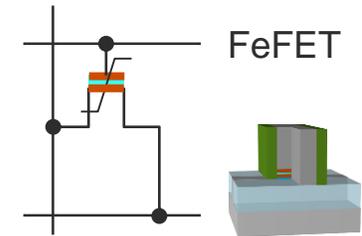
- Ferroelectric FET for non-volatile memory
- Extension to storage class memory
- Extension to neuromorphic devices (memorizing synaptic weight)



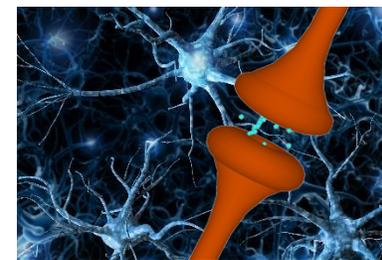
FeRAM



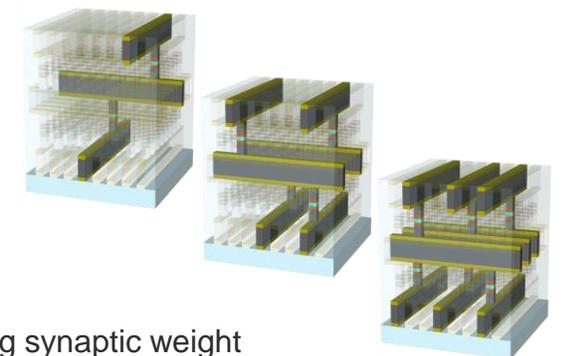
FeFET



Neuromorphic



Artificial synapse

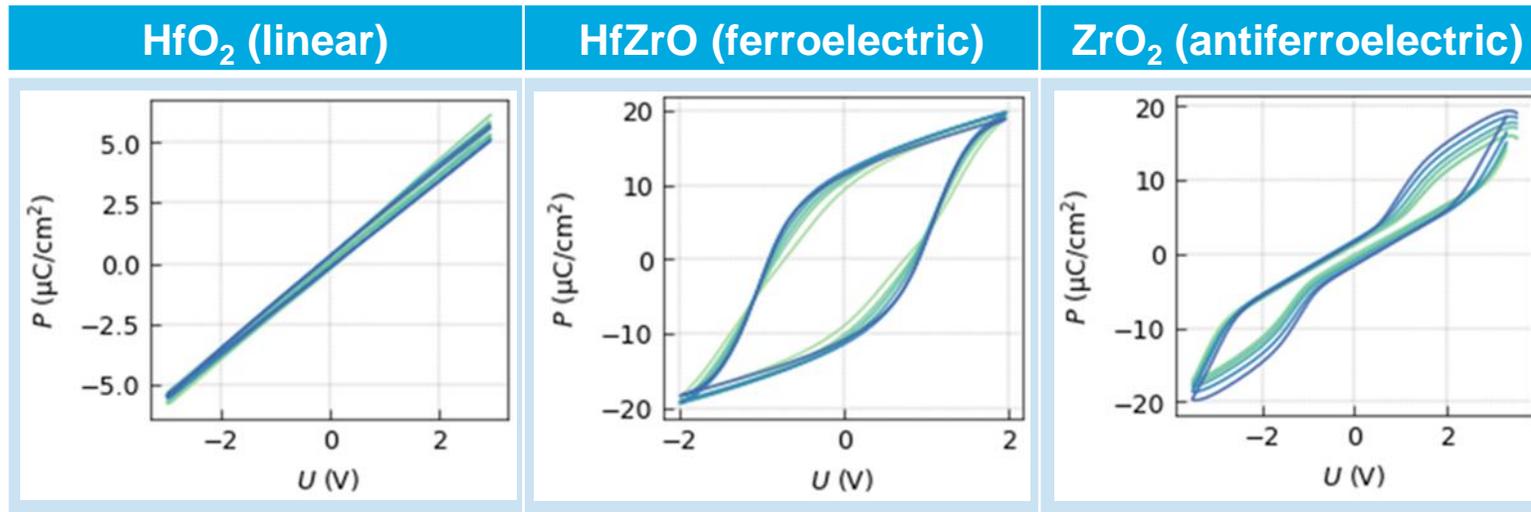


Memorizing synaptic weight

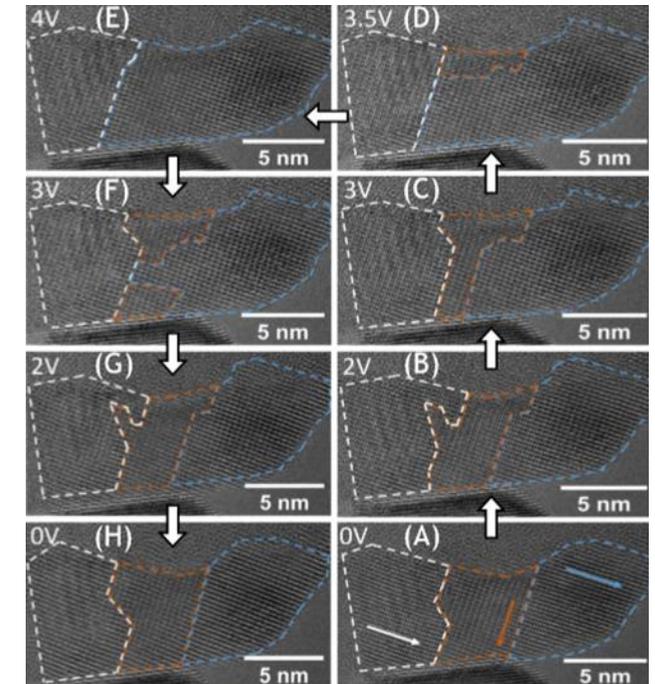
# Triase<sup>+</sup>™ EX-II™ MS: Multi-source Supply for Controllable Film Composition

Under development

## Ferroelectric properties



Multi-source supply enables controllable film composition, making possible the formation of various functional films



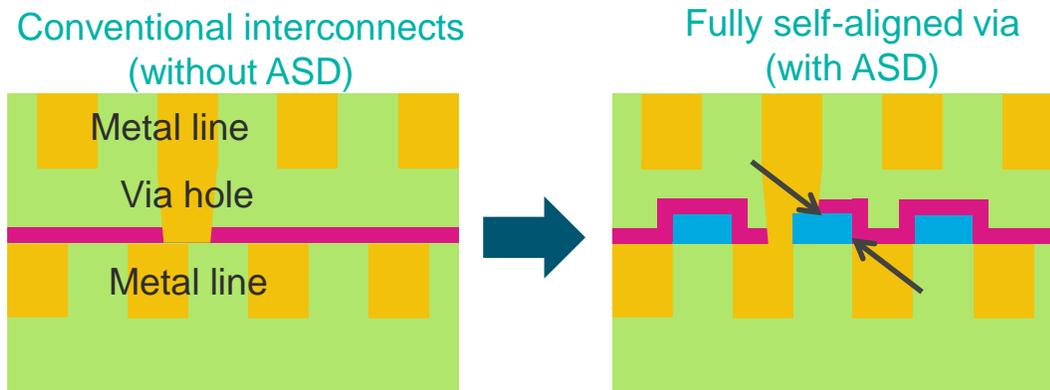
In-situ TEM measurement with simultaneous voltage cycling of antiferroelectric ZrO. Crystal grains grow and shrink by field driven domain wall migration as the voltage cycles from 0V→4V→0V.

Demonstrated at TEL Technology Center, America.

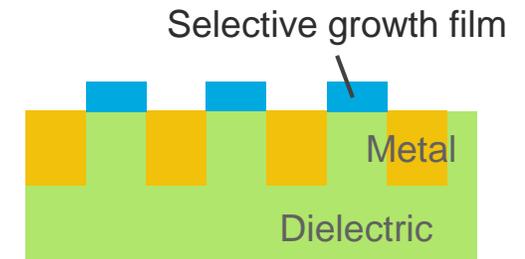
Reference: Lombardo *et al.*, VLSI 2020

# New Opportunity: Area Selective Deposition for Sustainable Scaling

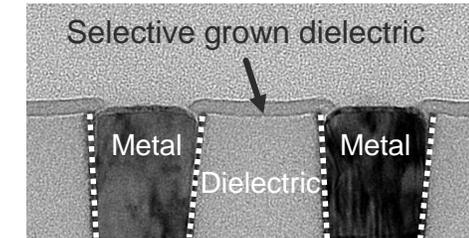
- Features
  - Selective growth of film on metal/dielectric surface
  - Excellent surface pre-treatment technology for high selectivity between growth and non growth surfaces
- Applications
  - Logic BEOL, Fully Self-Aligned Via (FSAV)
  - To every scaled patterning for enhancing lithography misalignment margin



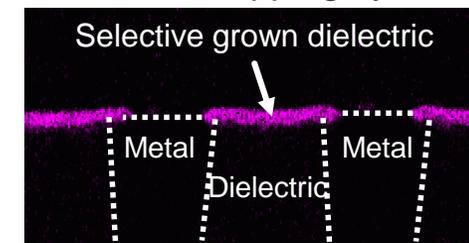
## Area selective deposition (ASD)



Cross-sectional image by TEM



Elemental mapping by EDX



@TEL internal structure

Reference: S. Azumo, 32<sup>nd</sup> symposium, SCEJ

# Summary

- TiN for super high aspect ratio
  - Sustains DRAM capacitor scaling
  - Enhances word line performance in 3D NAND
- High quality high-k dielectric
  - Newly adopted for DRAM peripheral high-k metal gates
  - Enhances control gate performance in 3D NAND
- Multi-source supply
  - Realizes controllability of film composition
- Area selective deposition
  - Enlarges misalignment margins in patterning

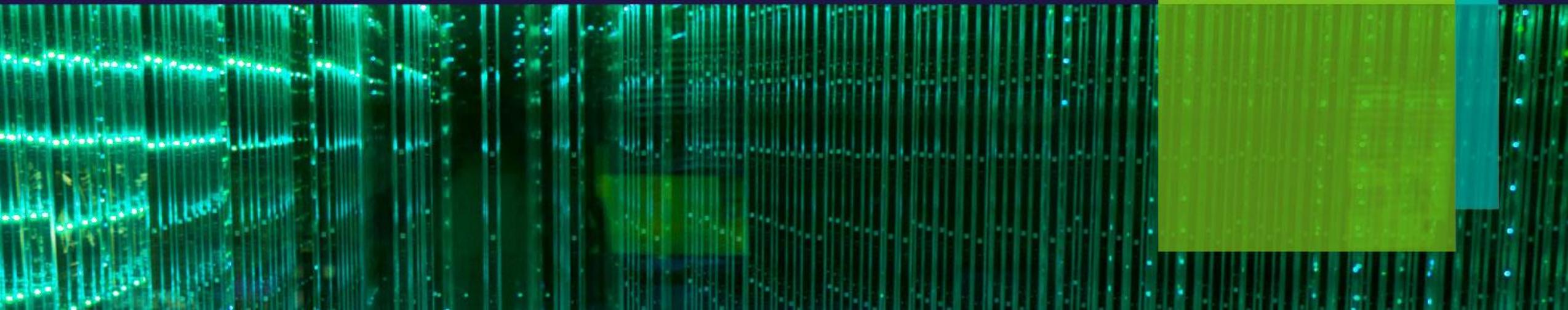


Triase<sup>e+</sup>™

# TEL's Strategies toward Digital Transformation

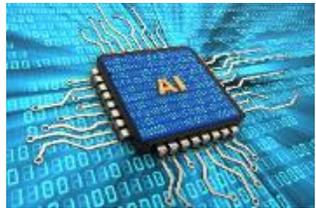
January 20, 2021

Noritaka Yokomori  
Deputy General Manager, Corporate Innovation Division



# TEL's Vision for Digital Transformation

- Industry as a whole is increasingly adopting digital transformation (DX), and the semiconductor industry is no exception. DX occupies an important position as one piece of the solution to demand for further scaling and multi-layering



AI chips



Autonomous



Cloud services

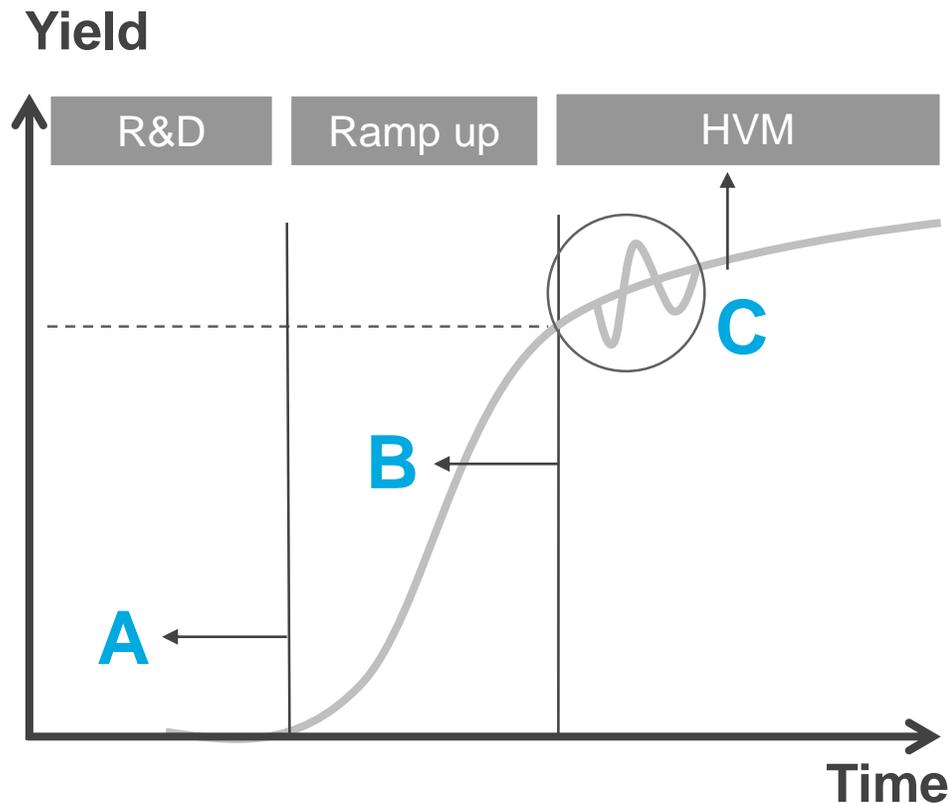


AR/VR

## TEL DX Vision

A global company where all employees drive enterprise value creation sustainably through activities such as value addition and efficiency improvements by leveraging digital technology

# DX in Contributing to Customers' Value Creation



## Potential Application

## Example

**A Shorter R&D TAT**

Swift POR proposal via accurate simulation

**B Shorter ramp up**

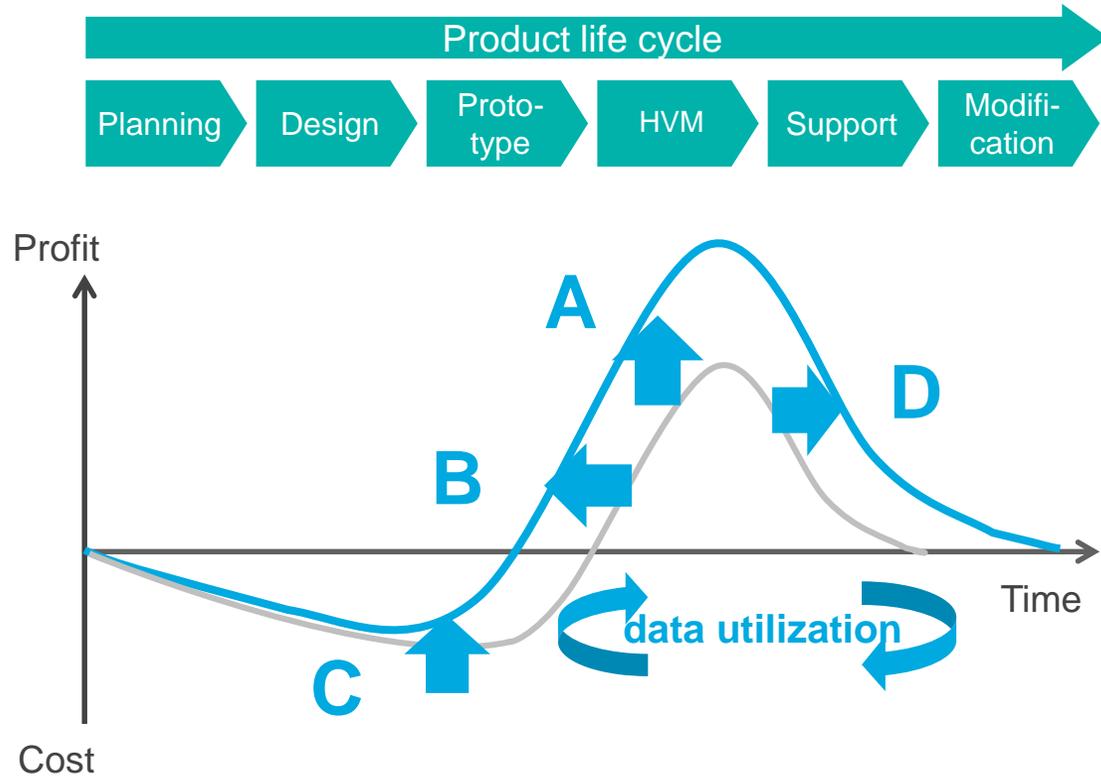
Chamber-to-chamber matching, automatic adjustment functions

**C Improved productivity/yield**

Predictive maintenance, fault detection, process adjustment functions via monitoring and analysis functions

From development to production, contributes to customers' value creation in a range of settings

# DX in Raising Capital Efficiency



## Potential Application

- A Higher profitability**
- B Shorter time to market**
- C Lower production cost**
- D Extended lifetime value**

## Example

Provide high value-added products that contribute to customers' value creation

Shorter development period through more efficient development environment

Lower number of prototypes by using simulation

Propose appropriate maintenance/modifications

From product planning to maintenance,  
raises capital efficiency in a range of settings

# DX Activities

## Digital enablers

- High-performance computing
- Cloud infrastructure
- AI technology
- IoT, xR

## Surrounding environment

- Progress in data sharing and collaboration in supply chains
- High expectations for AI and robot support of humans

## Added value creation/improved capital efficiency

**3. Control**  
Feedback to the real world

**1. Monitoring**  
Visualization

**4. Autonomy**  
Autonomous learning and decision-making

**2. Analysis and prediction**  
Analysis and prediction with digitalized data

## Achieving goals

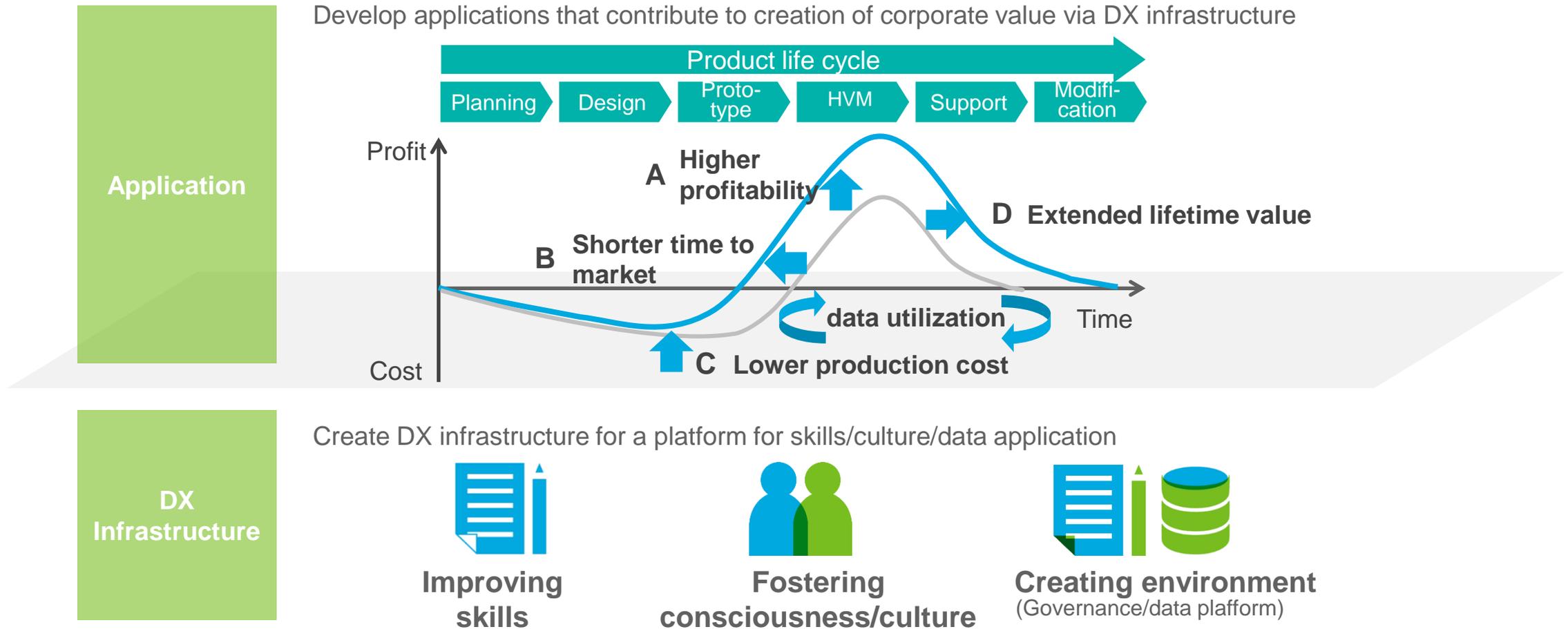
- Resolution of high value problems

### High value problem

- Quality
- Cost
- Speed
- Productivity
- Energy consumption

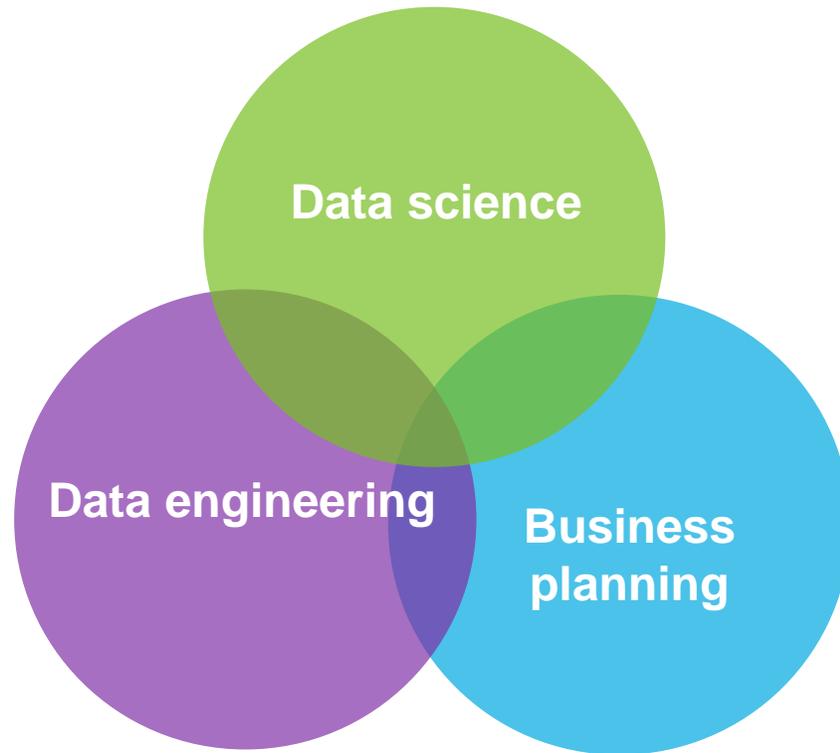
Digital transformation in resolving high value problems

# Overall Image of TEL's DX Project



Utilize DX infrastructure to develop applications that create corporate value

# DX Engineer Training Plan



## Data science

Ability to understand and utilize data science, such as data processing, AI and statistics

## Data engineering

Ability to give meaningful shape to data science for TEL's efforts to create corporate value, and to implement and operate in line with targets

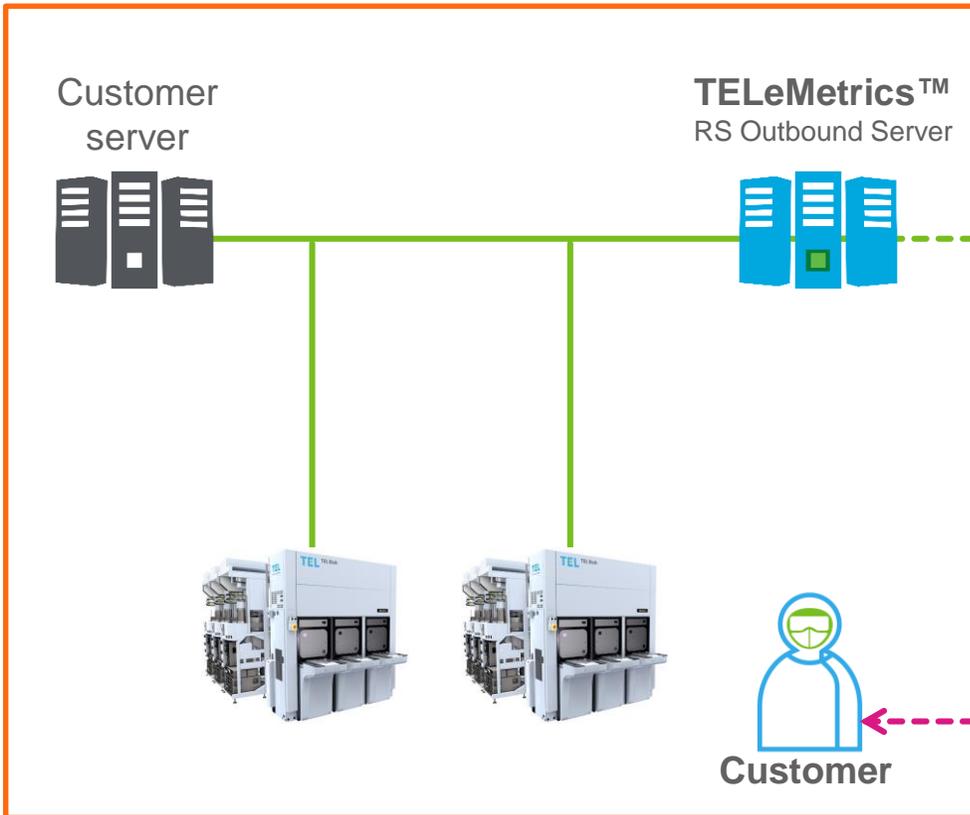
## Business planning

Ability to evaluate issues and their context, implement measures to resolve them, and link this to business (earnings ability)

Systematically train human resources to utilize data science in TEL's business

# TELeMetrics™: Remote Connection with Customer Fabs

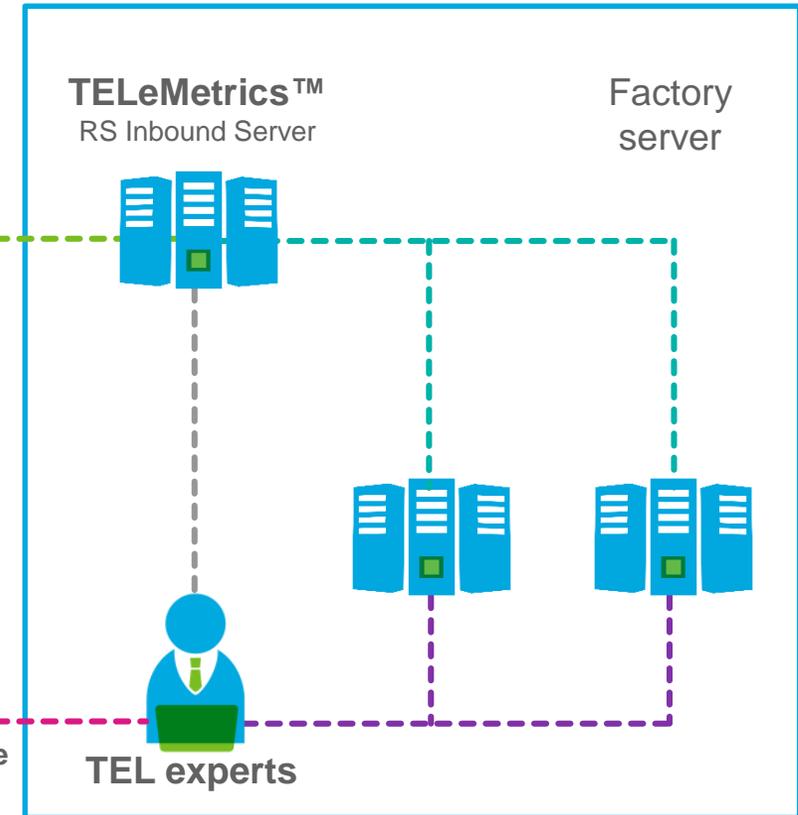
## Customer site



## Data from tool



## TEL



Transformation from selling man-hours to selling value

# Remote Support Using AR

## Customer's cleanroom



## TEL support center



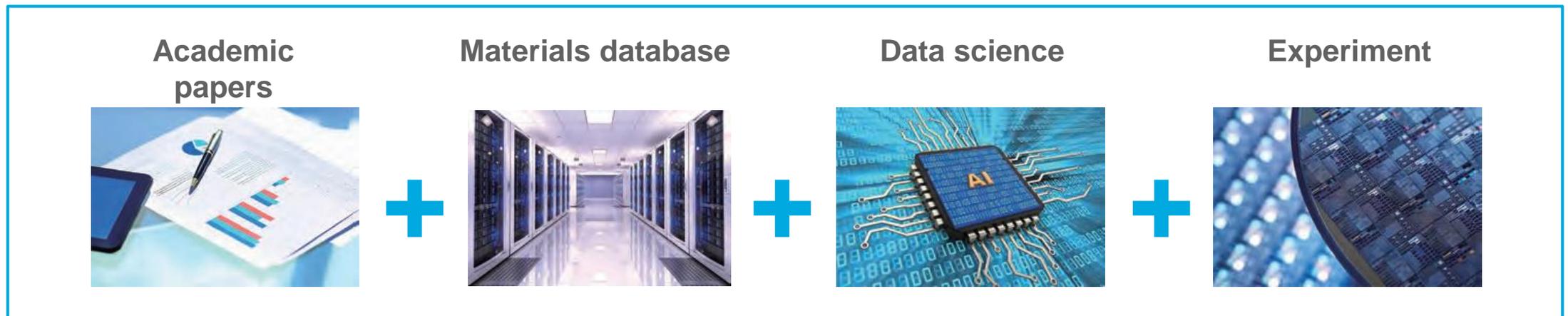
AR: "Augmented reality"; technology that can overlay information on a view of the real world via smart glasses

Apply new technology in this era of big data  
to enhance service efficiency

# Exploring Materials Through AI

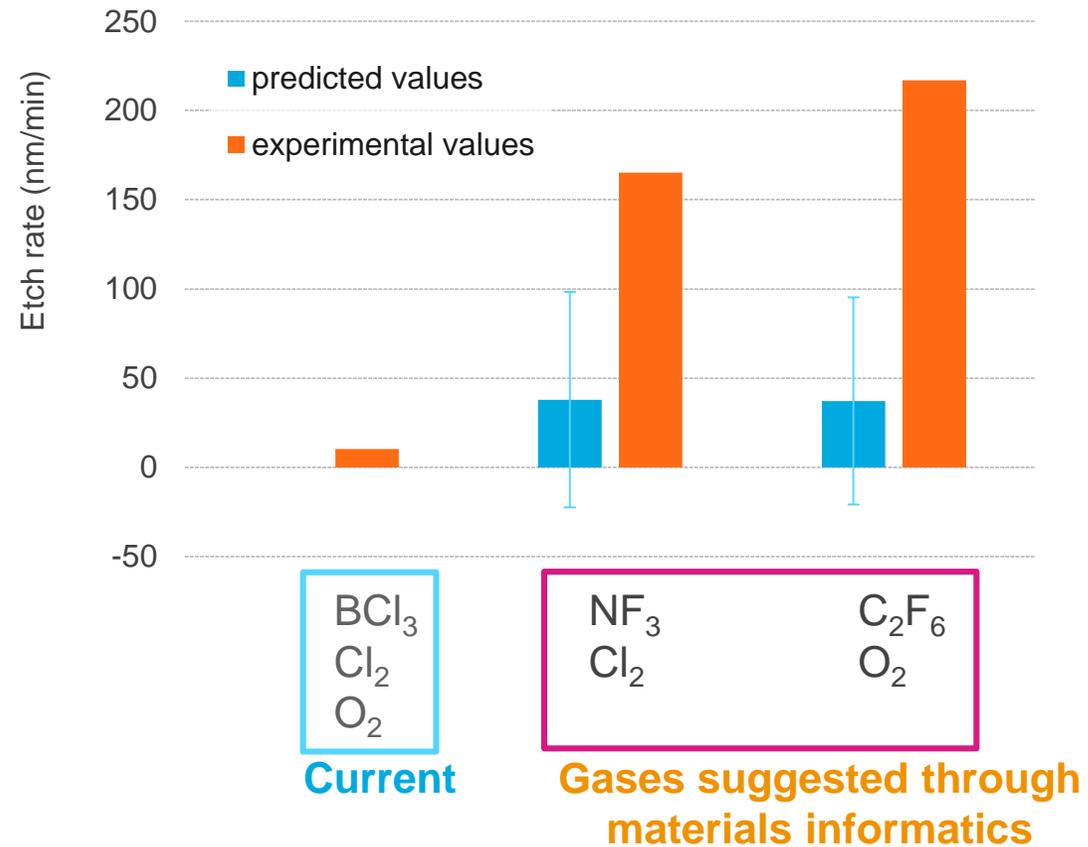
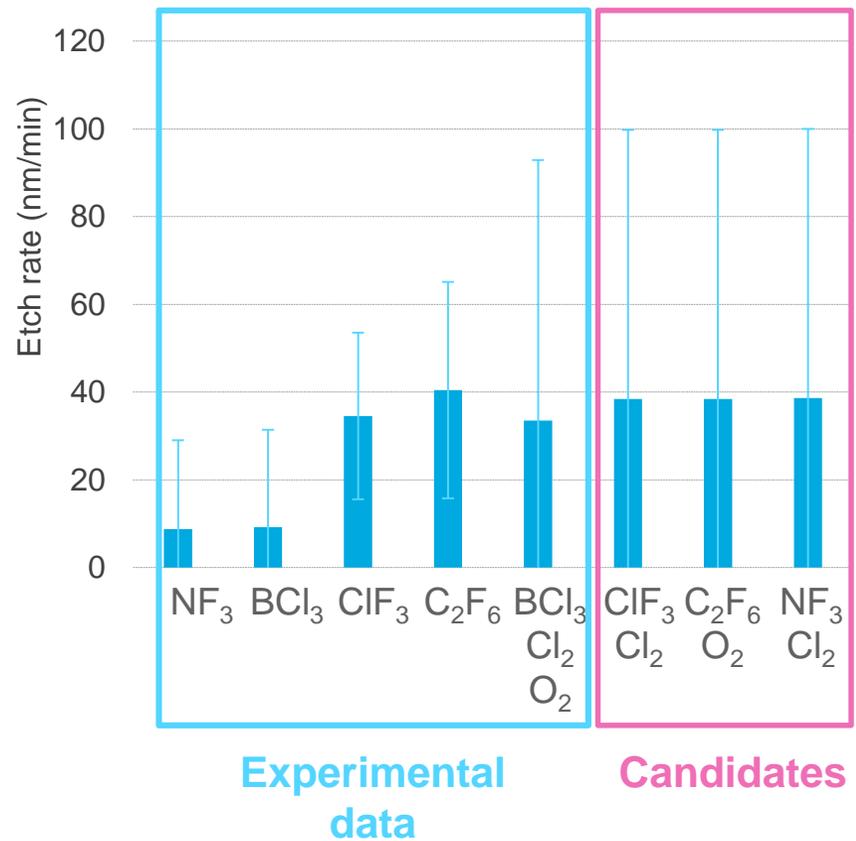
A way to co-optimize process requirements and materials

## Materials informatics



Explore materials for use in etching metal oxides

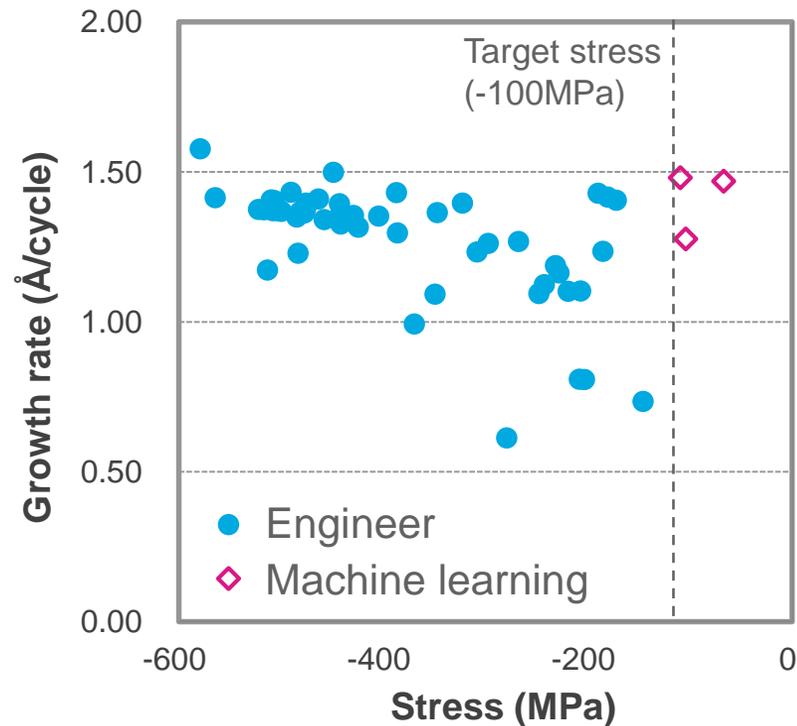
# Comparison of Predicted and Experimental Values



Gases with higher etch rates than before were suggested using machine learning

# Process Optimization Through AI

## Plasma atomic layer deposition (PE-ALD) film stress adjustment



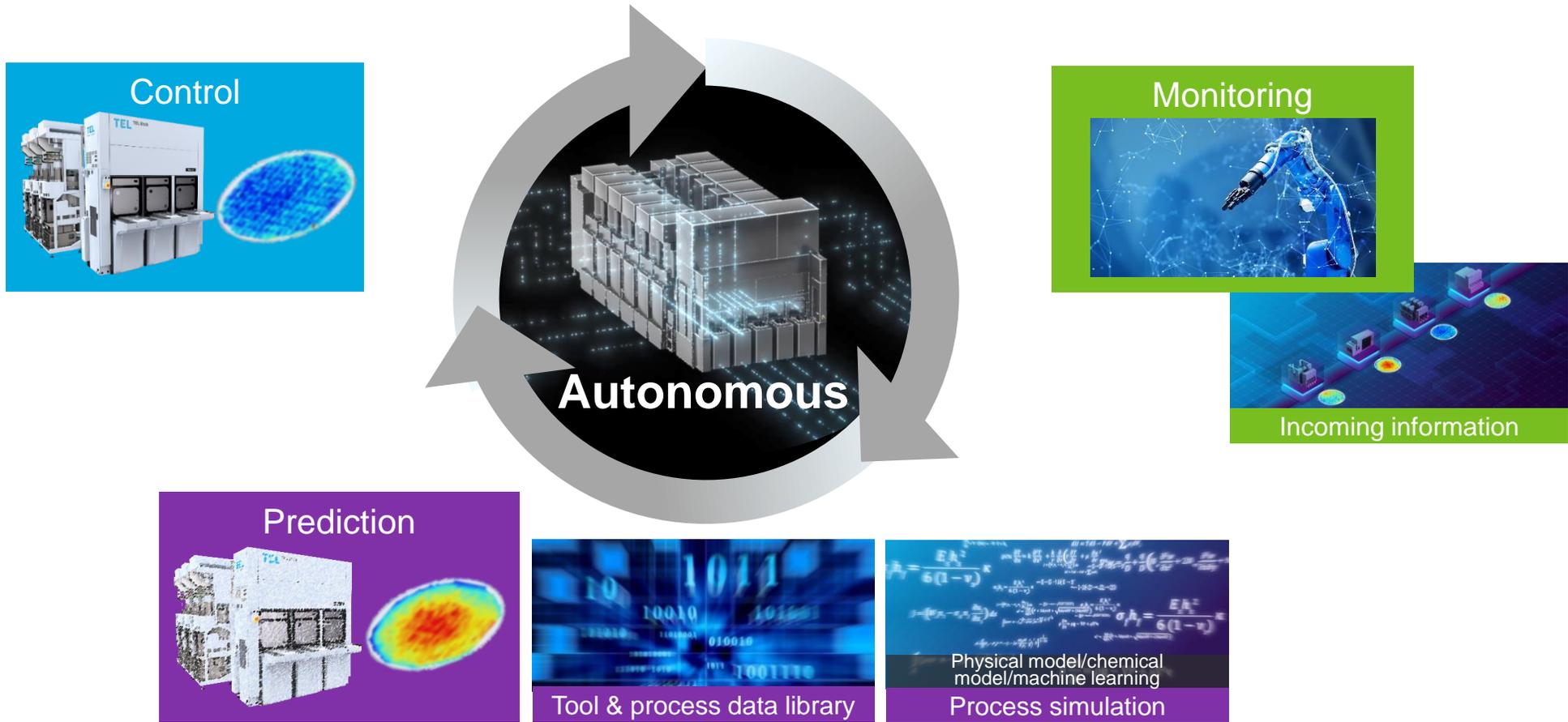
**Process: PE-ALD SiO<sub>2</sub> deposition**

**Target: film stress → between -100MPa 0MPa**

- Previous method using engineers
    - Unable to achieve target film stress levels
    - Gathered test data, studied with AI
- 
- Optimization through machine learning
    - Achieved target stress levels

Machine learning demonstrated the capability of process optimization

# Supporting Customer Value with Autonomous Equipment



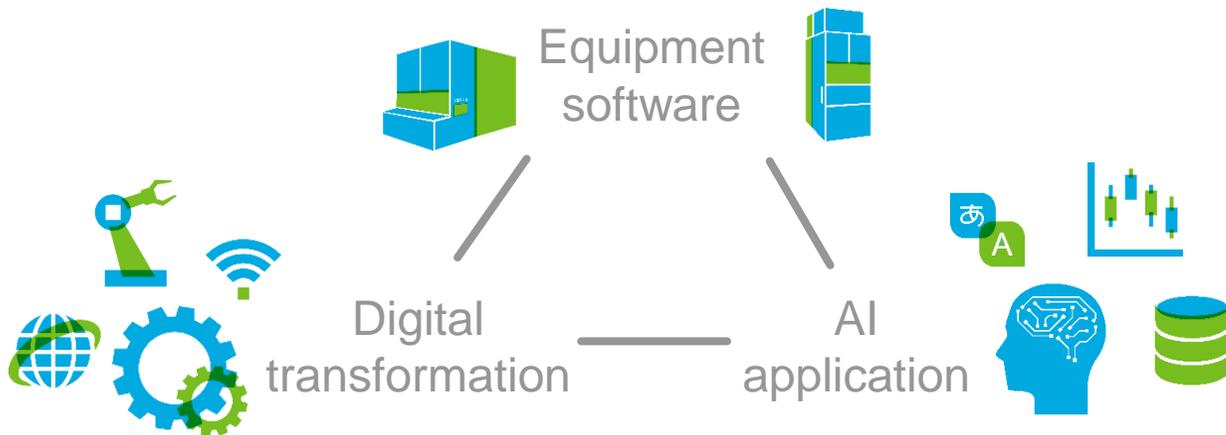
Autonomous learning by gathering necessary information  
Equipment senses its environment and state to maintain optimal status

# TEL Digital Design Square

## TEL DX Vision

A global company where all employees drive the sustainable creation of enterprise value by leveraging digital technology in activities including adding value and raising efficiency

## Development activities



## State-of-the-art office



Grand Opening  
November 24, 2020

Proudly celebrating 30 years  
in Sapporo, Hokkaido, Japan



Opened the TEL Digital Design Square as the home base for DX activities

# TEL Digital Design Square Movie

**TEL**™

**TOKYO ELECTRON**